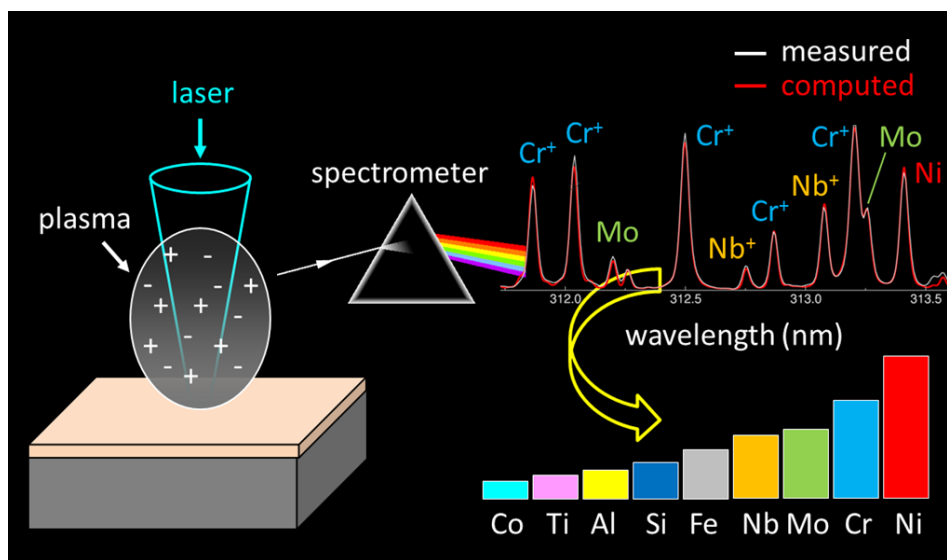


Analyse LIBS sans étalonnage



Jörg Hermann

LP3, CNRS, Aix-Marseille Université, 13009 Marseille

Calibration-free LIBS

Introduction

- Principle and historical background

Validity conditions of physical model

Methods of calibration-free measurements

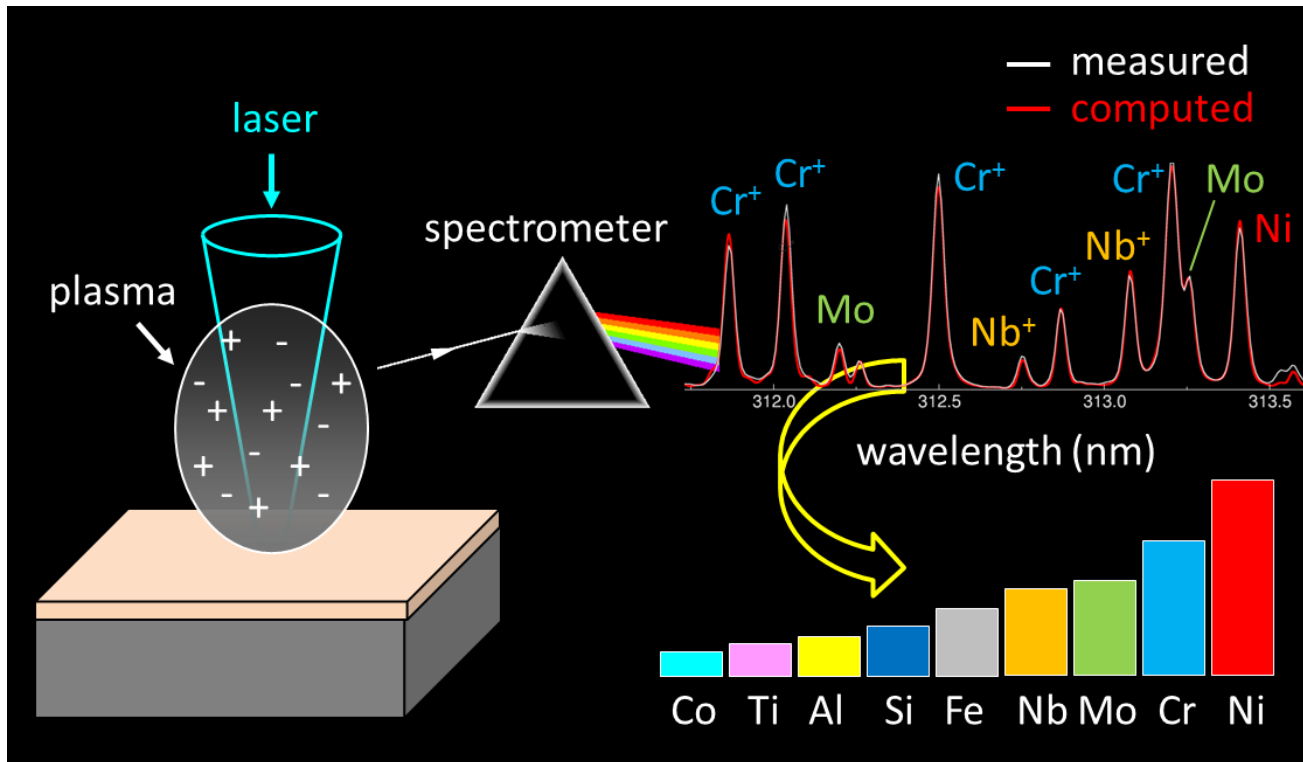
Critical review of analytical performance

Recommendations

Practical advice

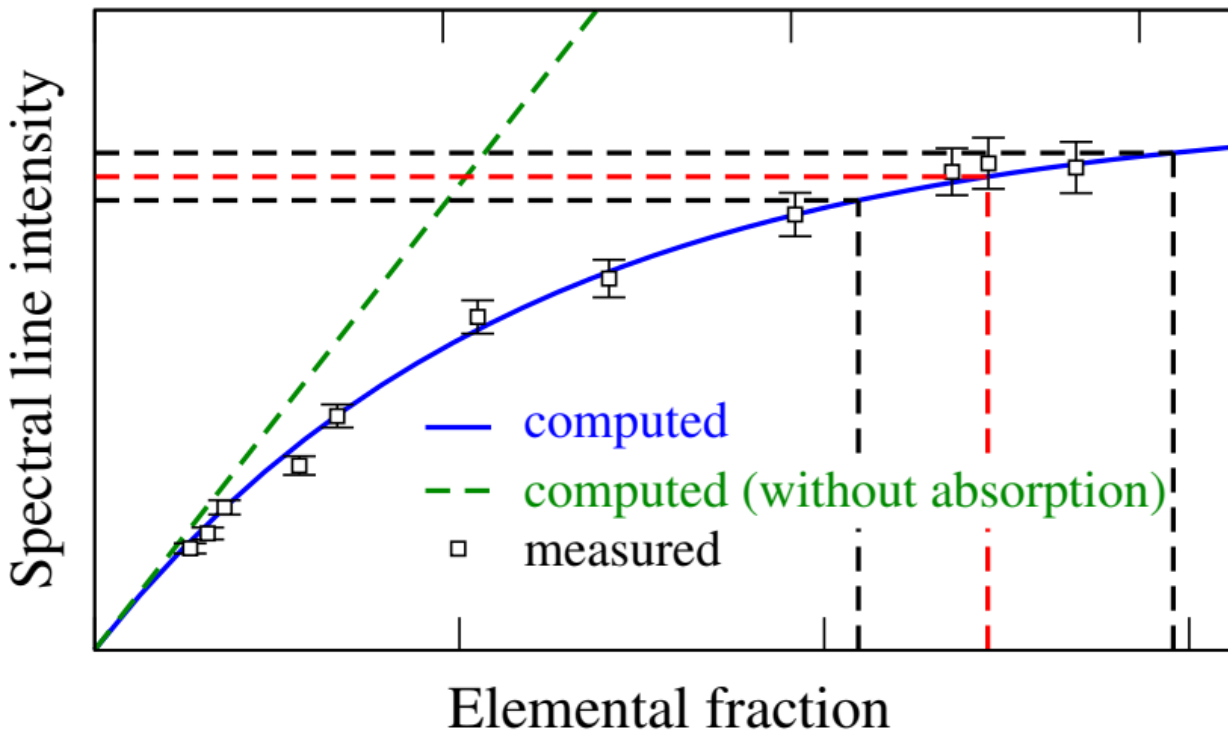
Principle of calibration-free LIBS

- 👉 modeling of plasma emission spectrum
- 👉 comparison to measured spectrum



Principle of calibration-free LIBS

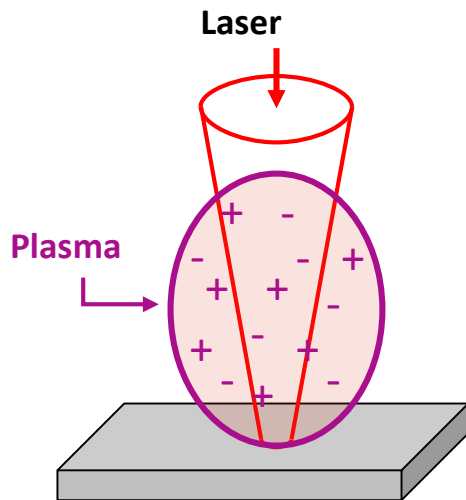
☞ calibration curve generated by calculation



Principle of calibration-free LIBS

☞ CF-LIBS requires model for spectrum calculation

multielemental plasma ☞ unique model enables this calculation



☞ Local thermodynamic equilibrium (LTE)

Is the laser-induced plasma in LTE ?

Plasma produced by laser ablation

+ large initial density

- fast expansion dynamics

⇒ conclusion about LTE is not straightforward

Historical background



- 1978 : validity of LTE in laser-produced plasma, *Eliezer et al. J. Phys D*

A generalised validity condition for local thermodynamic equilibrium in a laser-produced plasma

Shalom Eliezer, Aaron D Krumbein and David Salzmann
Department of Plasma Physics, Soreq Nuclear Research Centre, Yavne, Israel

Received 9 January 1978

☞ **theoretical investigation**

☞ **experimental validation difficult**

- low plasma reproducibility

- limited experimental means for time-resolved broadband spectra recording

Historical background

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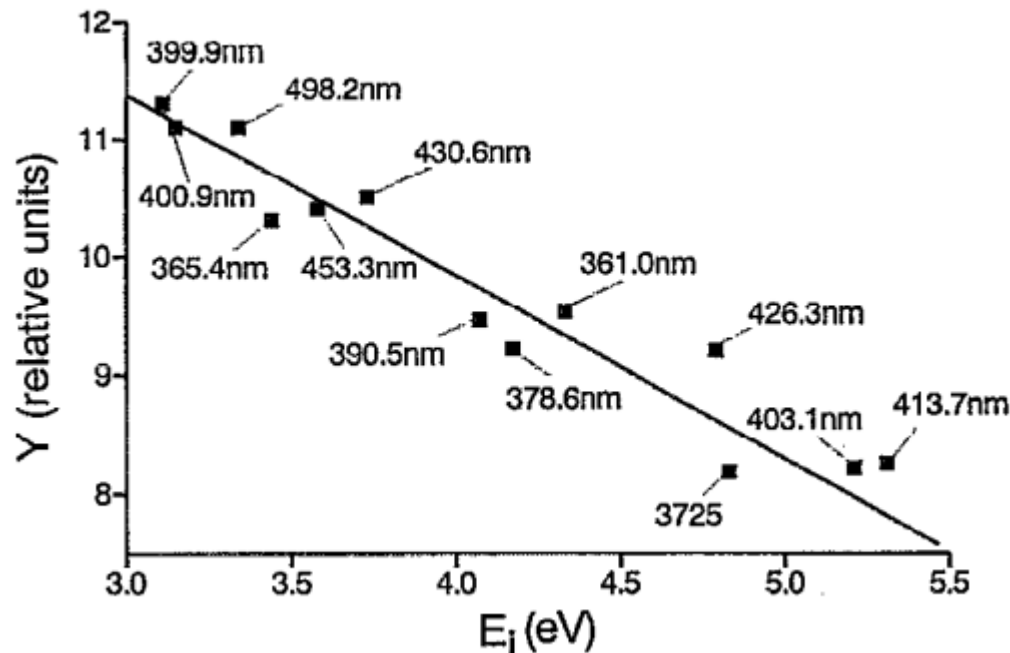


FIG. 7. Boltzmann diagram of Ti I. Delay with respect to the laser pulse: $t=1 \mu\text{s}$, $E_{\text{las}}=53 \text{ mJ}$ (short laser pulse), $p_0=400 \text{ Torr}$, $d=1.0 \text{ mm}$.

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⇒ temperature evaluation

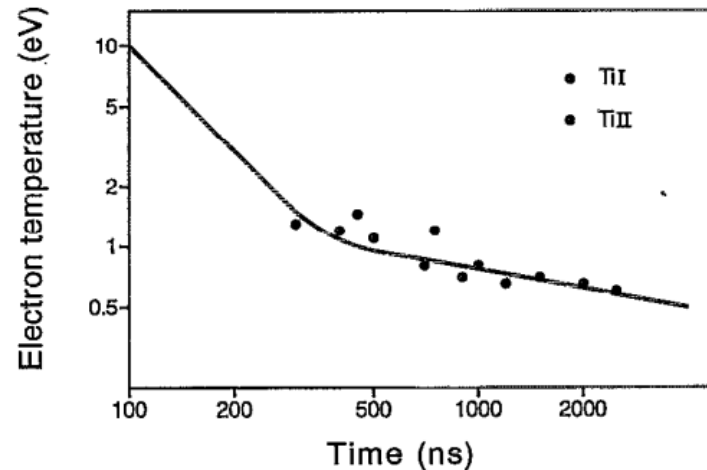
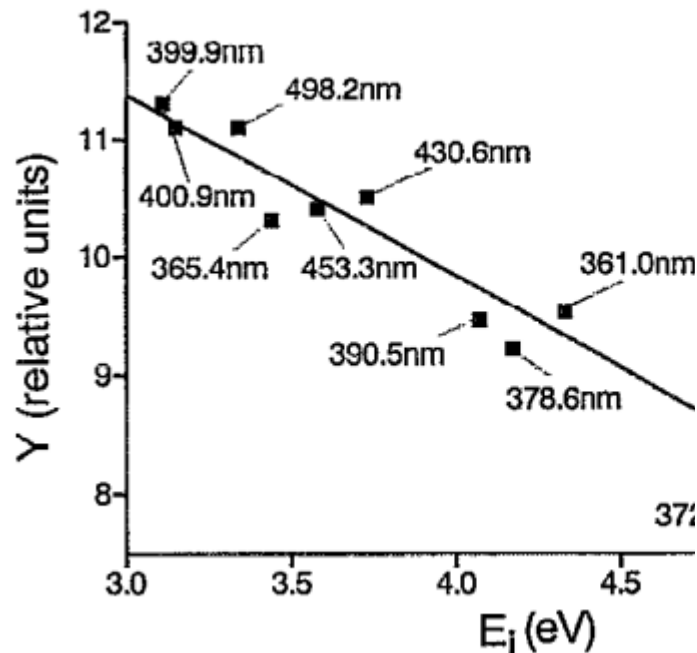


FIG. 8. Temporal evolution of electron temperature deduced from Ti I and Ti II Boltzmann diagrams. $E_{\text{las}}=53$ mJ short laser pulse $p_0=400$ Torr, $d=1.0$ mm. The value 10 eV for 100 ns is deduced from LTE calculations.

FIG. 7. Boltzmann diagram of Ti I. Delay with respect to the laser pulse: $t=1$ μs , $E_{\text{las}}=53$ mJ (short laser pulse), $p_0=400$ Torr, $d=1.0$ mm.

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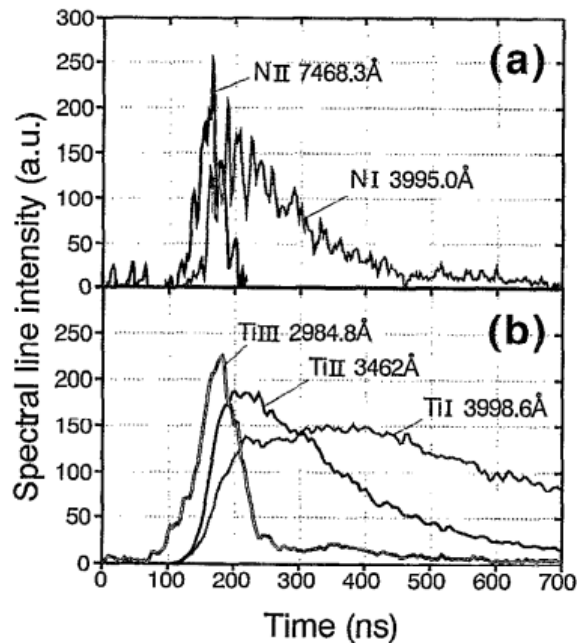


FIG. 9. Spectral line kinetics of neutral atoms and ions of (b) N and (a) Ti. $z=3$ mm, $p=0.5$ mb, $I_{\text{las}}=500$ MW cm⁻².

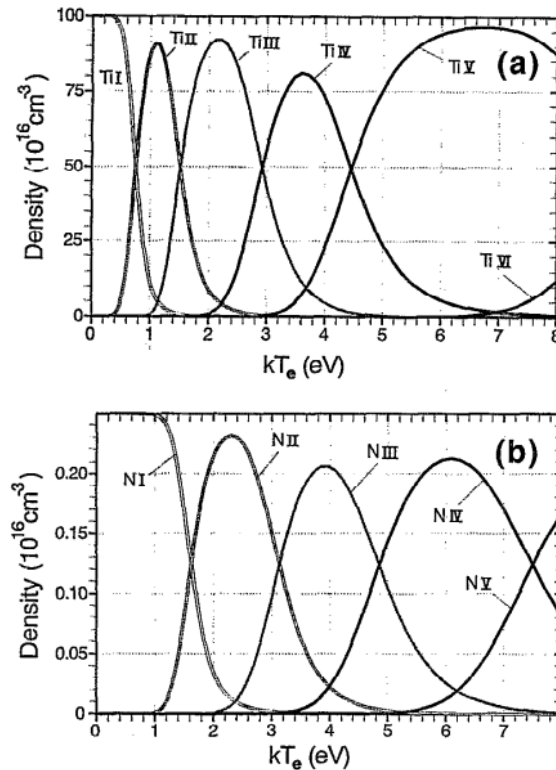


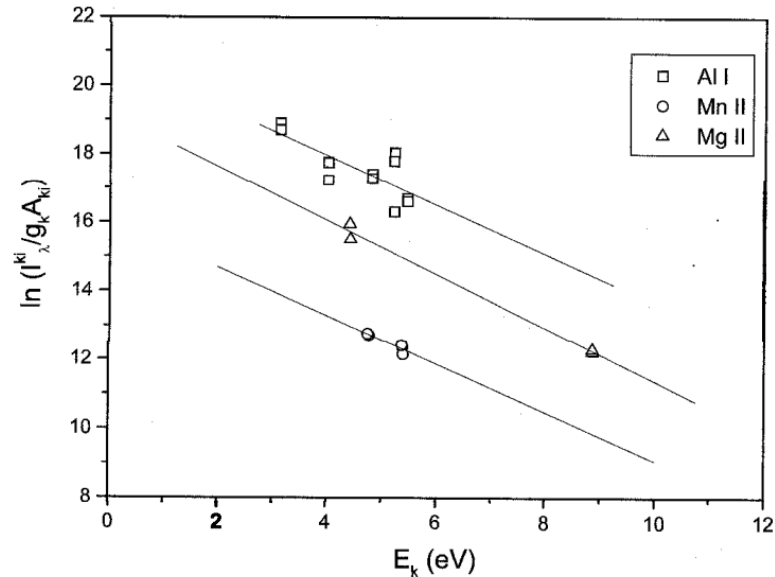
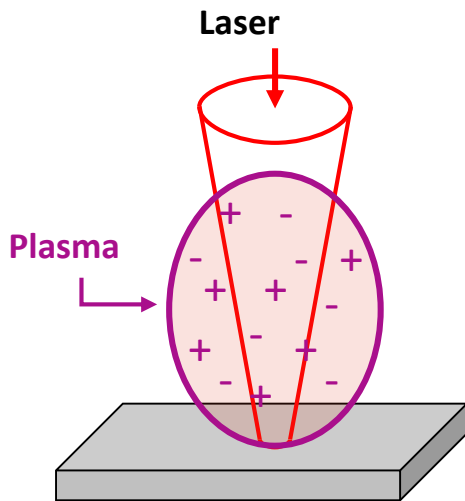
FIG. 8. Computed equilibrium densities of (a) Ti and (b) N species as a function of kT_e for 10^{18} cm⁻³ vapor density.

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☞ assumption of stoichiometric ablation

☞ multielemental Boltzmann plot

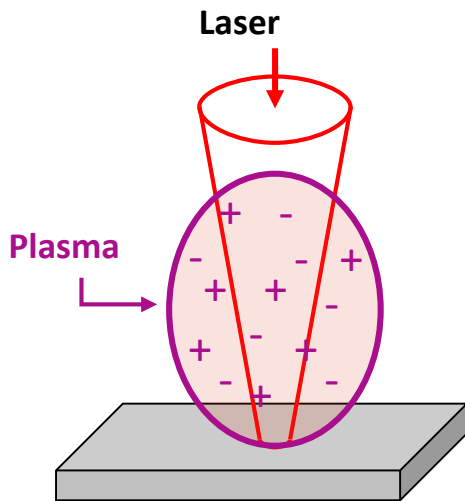


☞ easy to handle ⇒ large success

Historical background

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👉 low analytical performance

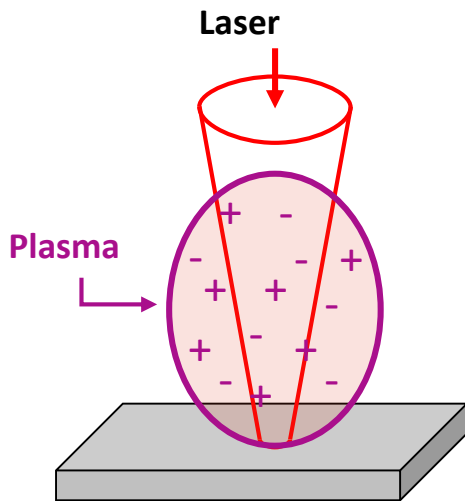


hypotheses :

- stoichiometric ablation ✓
- local thermodynamic equilibrium ✓
- plasma uniform (✓)
- plasma optically thin **no**

Historical background

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- > 1999 : amended CF-LIBS approaches, most devoted to correction of self-absorption



hypotheses :

- **stoichiometric ablation** ✓
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- **plasma uniform** (✓)
- ~~**plasma optically thin**~~

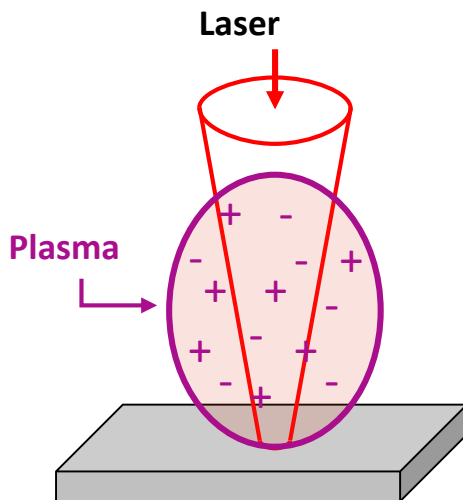
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- 1995 : comparison of plasma emission to LTE calculation, *Hermann et al. J. Appl. Phys*
- 1999 : invention of calibration-free LIBS, *Ciucci et al. Appl. Spectrosc.*
- > 1999 : amended CF-LIBS approaches, most devoted to correction of self-absorption
- ≥ 2008 : CF-LIBS based on spectra simulation

☞ **self-absorption intrinsically taken into account**

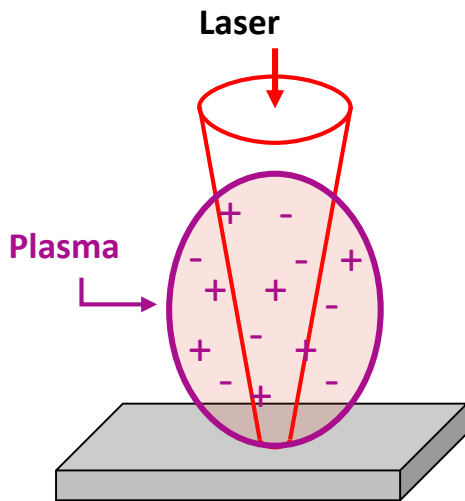
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- ~~**plasma optically thin**~~



Validity conditions of physical model

Mass transfer from solid towards plasma is congruent ?



hypotheses :

- **stoichiometric ablation**
- local thermodynamic equilibrium
- plasma uniform
- plasma optically thin

Validity conditions of physical model

Mass transfer from solid towards plasma is congruent ?

☞ question on mechanism of laser ablation

+ thermal evaporation

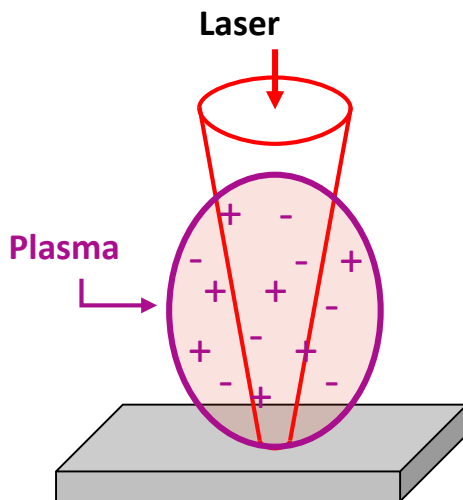
☞ element-dependent evaporation pressure (Clausius-Clapeyron equation)

⇒ **non-stoichiometric mass transfer**

+ phase explosion

☞ high laser intensity induces large rate of vaporization ⇒ **no time for segregation**

⇒ **stoichiometric mass transfer**



hypotheses :

- **stoichiometric ablation**
- local thermodynamic equilibrium
- plasma uniform
- plasma optically thin



Validity conditions of physical model

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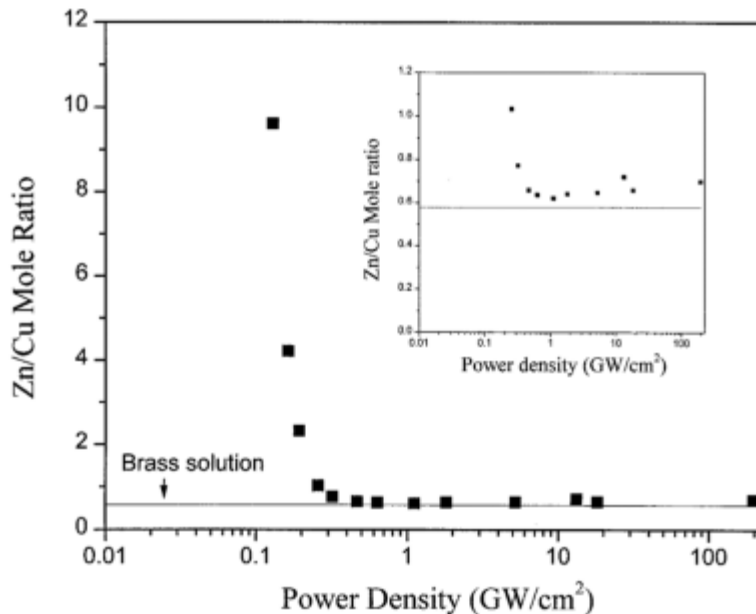
☞ high laser intensity induces large rate of vaporization ⇒ **no time for segregation**

⇒ **stoichiometric mass transfer**

☞ **stoichiometric ablation depends on laser intensity**

Validity conditions of physical model

Mass transfer from solid towards plasma is congruent ?



Mao et al., Appl. Spectrosc. 1998

Zn/Cu ratio in brass
measured via LA-ICP-AES

(Laser ablation inductively coupled plasma
atomic emission spectroscopy)

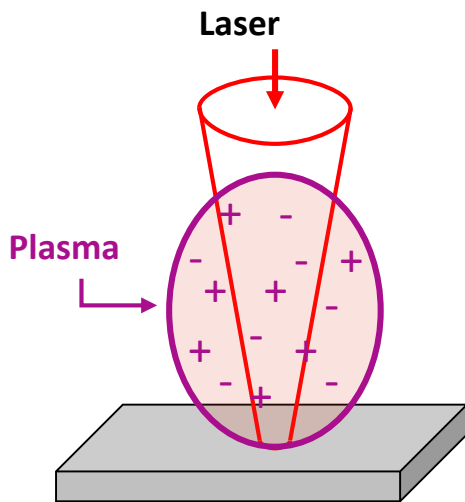
☞ **stoichiometric ablation depends on laser intensity**

in conditions typical for LIBS ($F_{las} = 100 \text{ Jcm}^{-3}$)

⇒ **mass transfer from solid to plasma stoichiometric**

Validity conditions of physical model

Plasma is in local thermodynamic equilibrium (LTE) ?



hypotheses :

- stoichiometric ablation
- **local thermodynamic equilibrium**
- plasma uniform
- plasma optically thin

Validity conditions of physical model

Plasma is in local thermodynamic equilibrium (LTE) ?

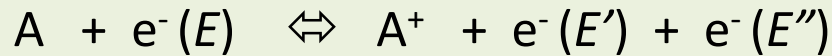
Elementary processes

collisional processes :

collisional excitation / desexcitation



electron impact ionization / 3 body recombination



radiative processes :

spontaneous emission / absorption (bound-bound transitions)



photoionization / radiative recombination (free-bound transitions)



bremstrahlung emission / inverse bremstrahlung absorption (free-free transitions)



out of equilibrium  collisional-radiative modeling

⇒ requires rates of all processes

Validity conditions of physical model

Plasma is in local thermodynamic equilibrium (LTE) ?

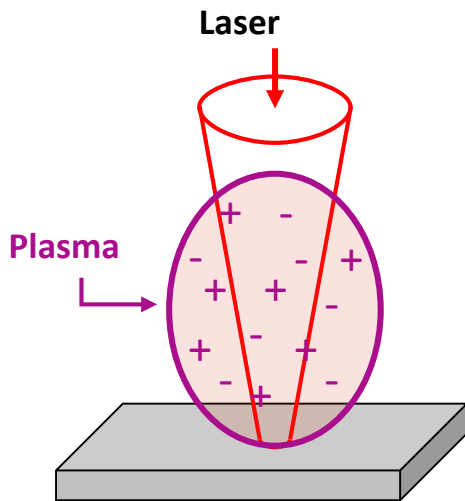
equilibrium \rightarrow principle of microscopic reversibility

\Rightarrow each process is counterbalanced by its reverse process

\rightarrow plasma of large size in steady state

laboratory plasmas \rightarrow size $<$ characteristic length of absorption

\Rightarrow **no microreversibility for radiative processes**



**equilibrium may still exist
if collisional processes dominate**

Validity conditions of physical model

Plasma is in local thermodynamic equilibrium (LTE) ?

high mobility of electrons (small mass)

⇒ collisional processes dominated by electrons

☞ **validity of LTE depends on electron density**

rates of collisional excitation / desexcitation $\Gamma_{ul}, \Gamma_{lu} \gg A_{ul}$

most difficult case ☞ the levels of largest energy gap ΔE_{max}

$$\text{LTE criterion : } n_e > 1.6 \times 10^{12} \sqrt{T} \Delta E_{max}^3 \quad (\text{McWhirter, 1965})$$

☞ **most elements : $n_e \geq 10^{16} \text{ cm}^{-3}$**

additional criteria :

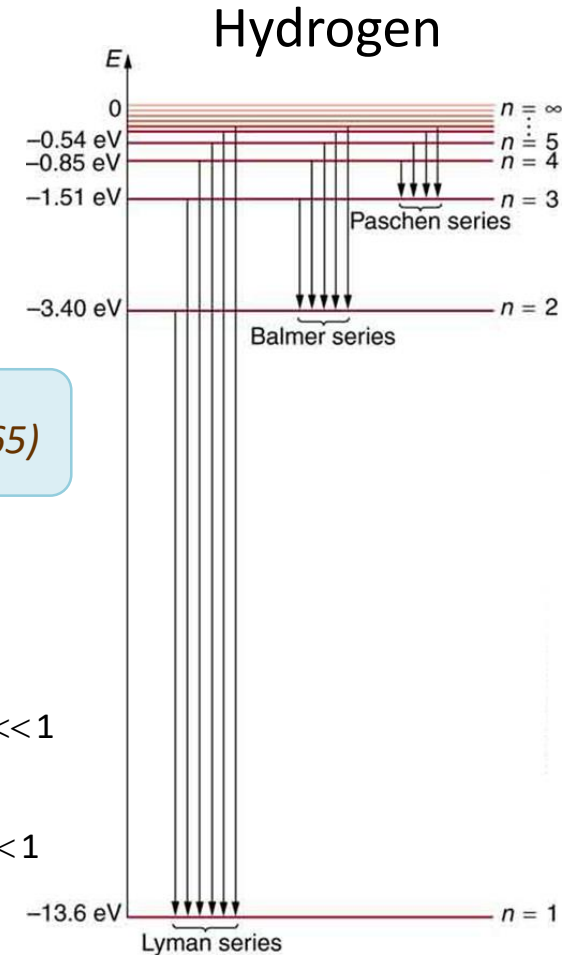
☞ **transient plasma**

$$\frac{T(t + \tau_{rel}) - T(t)}{T(t)} \ll 1 \quad \frac{n_e(t + \tau_{rel}) - n_e(t)}{n_e(t)} \ll 1$$

☞ **nonuniform plasma**

$$\frac{T(x) - T(x + \lambda)}{T(x)} \ll 1 \quad \frac{n_e(x) - n_e(x + \lambda)}{n_e(x)} \ll 1$$

$$\lambda = \sqrt{D \tau_{rel}} = \text{diffusion length during relaxation time}$$



Validity of LTE

👉 depends on experimental conditions

laser :

plasma density and lifetime depend on laser energy

⇒ sufficiently large E_{las} required

surrounding atmosphere :

plasma density and lifetime depend on gas pressure

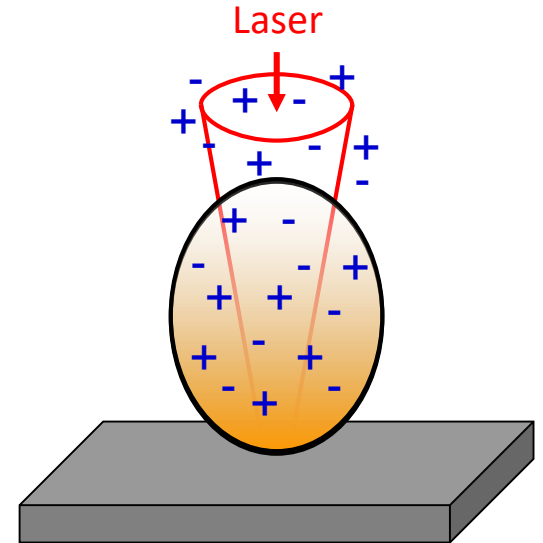
⇒ plume confinement by gas

sample material :

LTE validity depends on atomic structure

👉 atoms such as H, N, O, C have large ΔE_{max} ⇒ equilibrium hardly achieved

👉 metal have many close lying levels ⇒ equilibrium easily achieved



In conditions typical for LIBS analysis

nanosecond laser, E_{las} = a few mJ, at atmospheric pressure

👉 conditions of LTE achieved

Validity of LTE

Material ablation with a ns-laser

$$\left. \begin{array}{l} E_{las} = 10 \text{ mJ} \\ d_{spot} = 100 \text{ } \mu\text{m} \end{array} \right\} F_{las} = 100 \text{ Jcm}^{-2}$$

⇒ 10^{14} atomes ($\cong 10 \text{ ng}$)

☞ laser heats material to some 10^4 K

☞ plume expansion $u \cong \text{some } 10^3 \text{ m s}^{-1}$

$$t = 100 \text{ ns} \Rightarrow V = 0.1 \text{ mm}^3$$

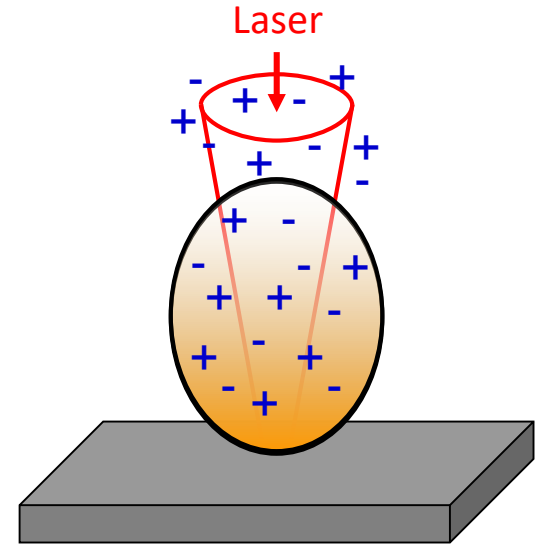
⇒ plasma density $\cong 10^{18} \text{ cm}^{-3}$

⇒ LTE valid

☞ further plasma evolution depends on surrounding atmosphere

$$\text{in air, } t = 1 \text{ } \mu\text{s} \Rightarrow n_e \cong 10^{17} \text{ cm}^{-3}$$

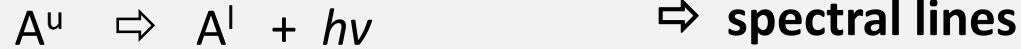
⇒ plasma in LTE for several μs



Validity of LTE

types of radiation :

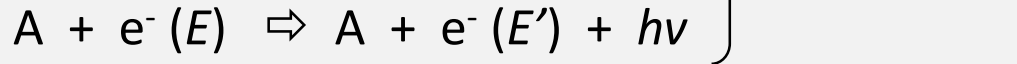
spontaneous emission



radiative recombination



bremstrahlung



intensity

$$\propto n_i = n \frac{g_i}{Q(T)} e^{-E_i/kT}$$

$$\propto n_e^2$$

plume expansion

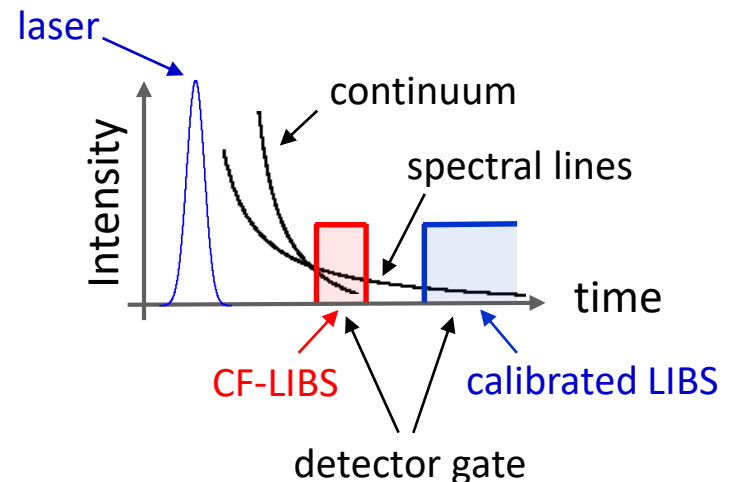
⇒ strong decrease of electron density

early expansion stage

☞ continuum dominates spectrum

setting the detector gate delay

☞ compromise LTE / signal-to-noise ratio



Validity conditions of physical model

Plasma is spatially uniform ?

laser ablation under vacuum

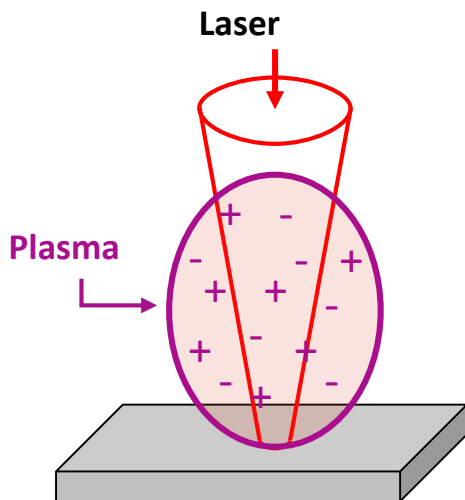
⇒ most energetic species in the expanding plume front

laser ablation in ambient gas

⇒ most energetic species at the vapor-gas contact front ($T_{border} > T_{core}$ at early time)

⇒ cooling of plume border by cold gas ($T_{border} < T_{core}$ at late time)

⇒ **time window expected for which the plume has an almost uniform T -distribution**



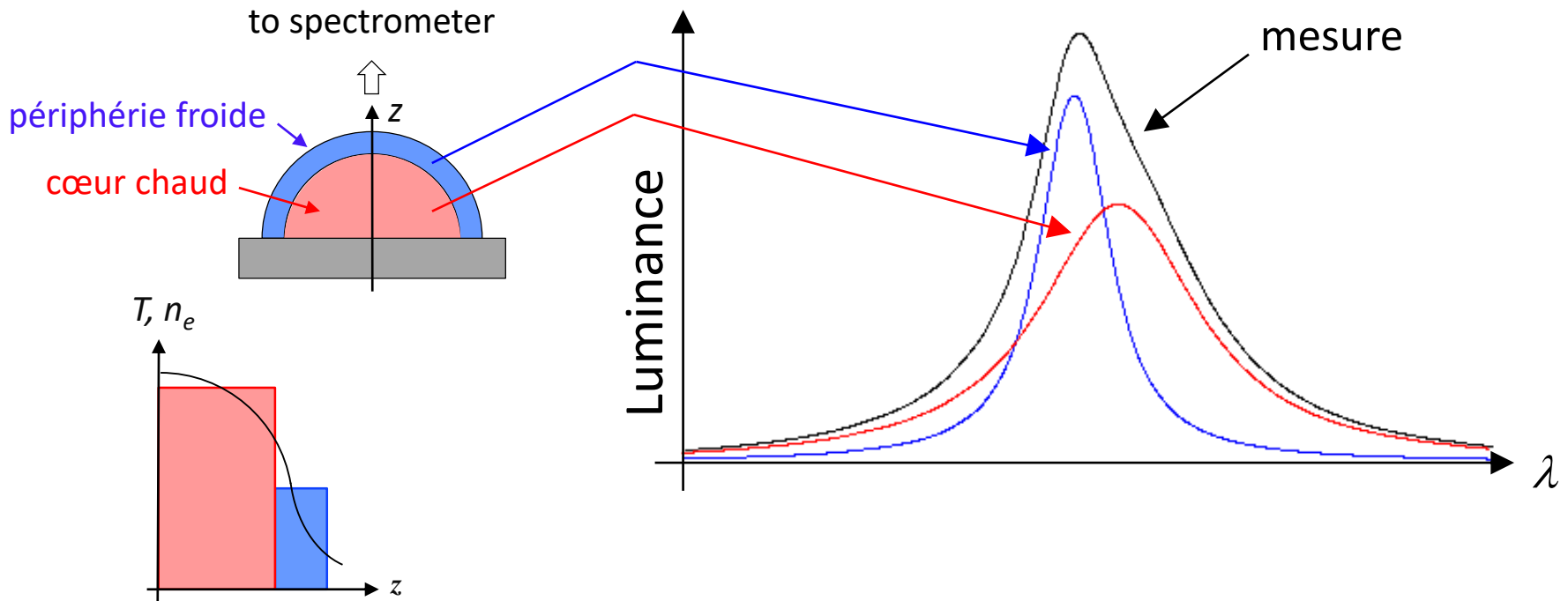
hypotheses :

- stoichiometric ablation
- local thermodynamic equilibrium
- **plasma spatially uniform**
- plasma optically thin

Validity conditions of physical model

Plasma is spatially uniform ?

Spectral shape of strongly Stark-shifted transition

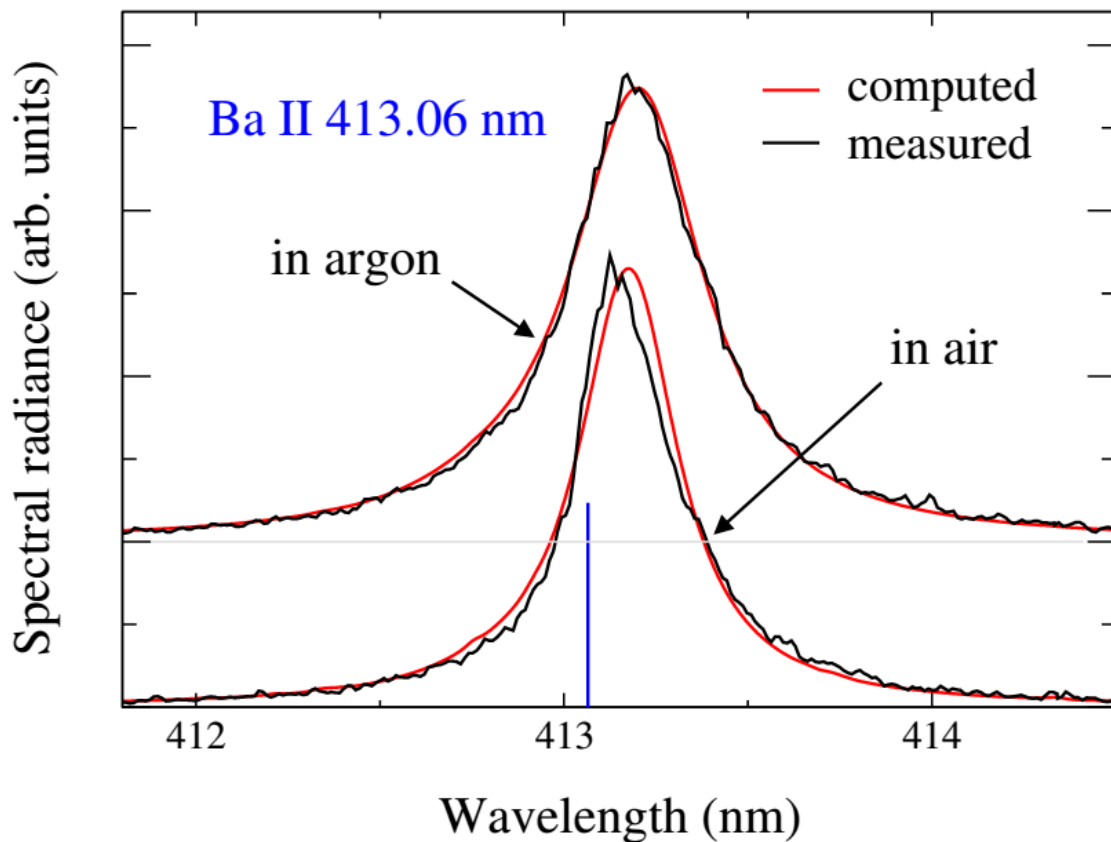


nonuniform plasma \Rightarrow **asymmetric profile**

Validity conditions of physical model

Plasma is spatially uniform ?

Spectral shape of strongly Stark-shifted transition



verre N-BaK4

$E_{las} = 6 \text{ mJ}$, $\lambda = 266 \text{ nm}$, $\tau = 5 \text{ ns}$

sous air

☞ plasma non-uniforme

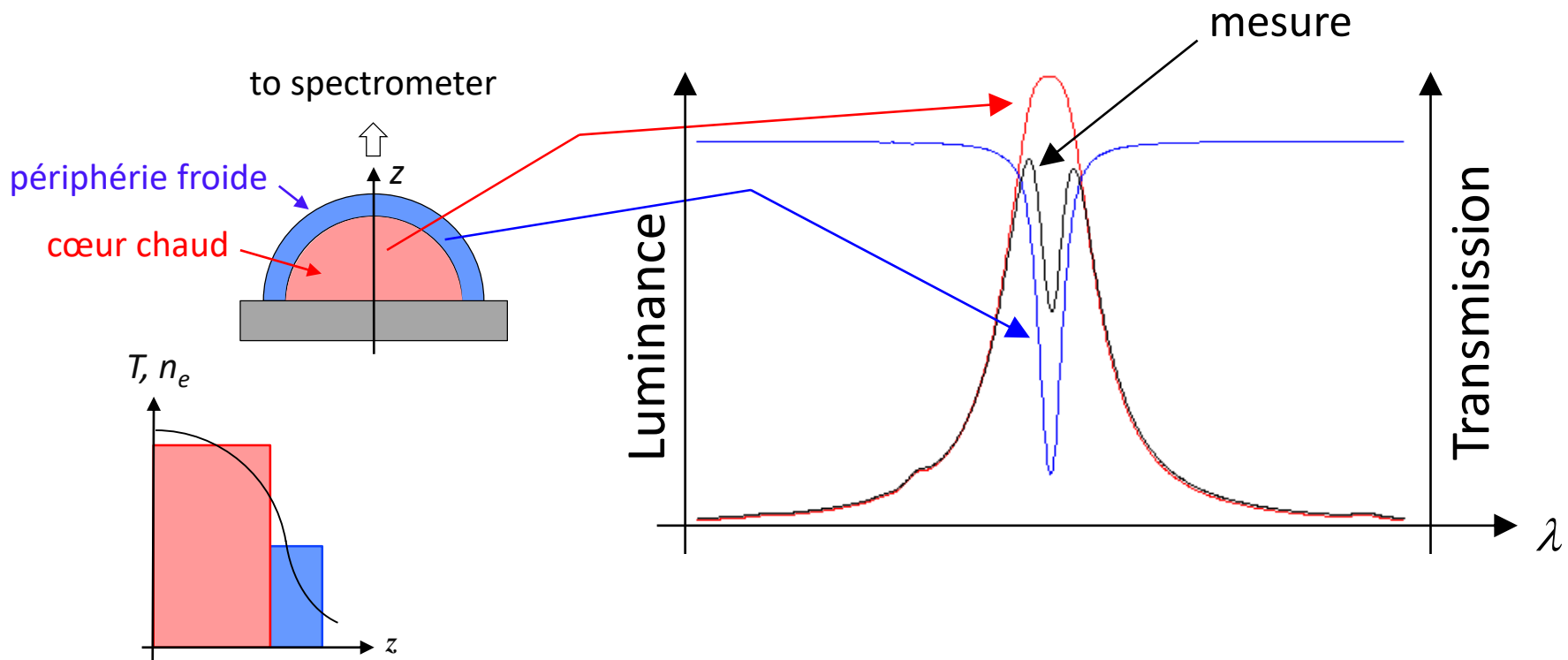
sous argon

☞ plasma uniforme

Validity conditions of physical model

Plasma is spatially uniform ?

Spectral shape of strongly self-absorbed resonance line

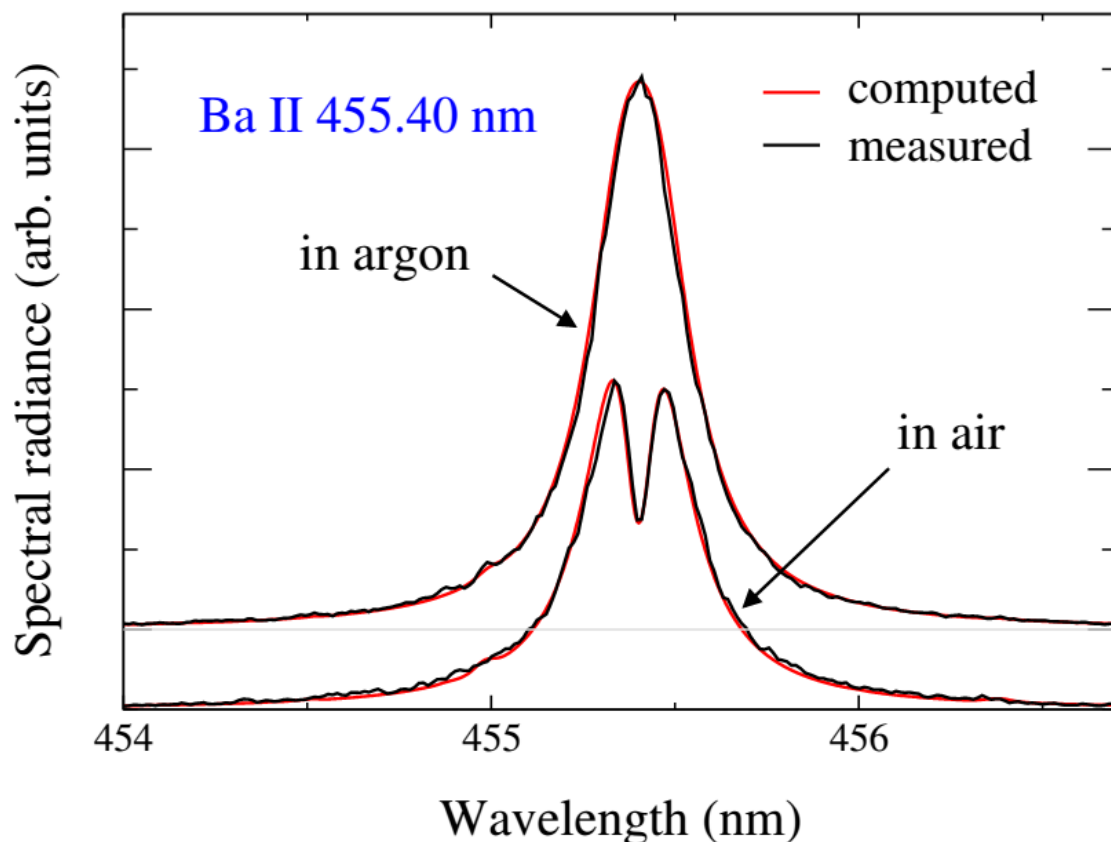


cold border \Rightarrow absorption dip

Validity conditions of physical model

Plasma is spatially uniform ?

Spectral shape of strongly self-absorbed resonance line



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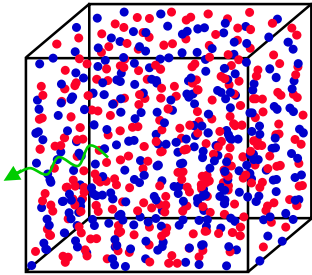
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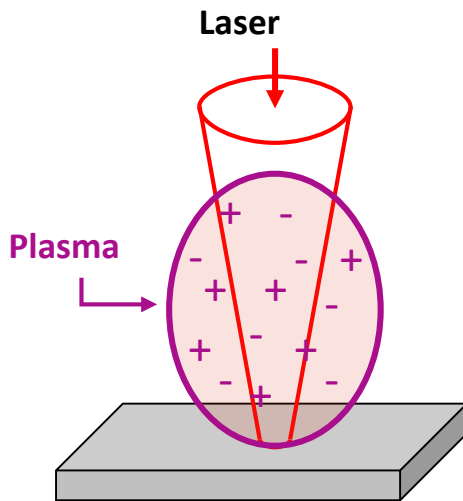
Validity conditions of physical model

Self-absorption is negligible ?

LTE validity requires high density ($n_e \geq 10^{16} \text{ cm}^{-3}$)



⇒ self-absorption significant



hypotheses :

- stoichiometric ablation
- local thermodynamic equilibrium
- plasma spatially uniform
- **plasma optically thin**

Methods of calibration-free measurements

Compositional measurements: the mathematical problem

mass fraction of element A : $C_A = \frac{n_A m_A}{\rho_{tot}}$

LTE plasma of M elements $\Rightarrow M + 1$ parameters

$\Rightarrow n_A$ of M elements and T

$\Leftrightarrow C_A$ of $M-1$ elements, n_e and T

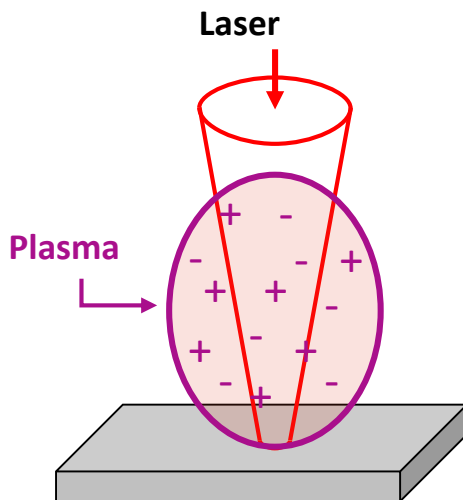
$$n_A = \sum_{z=0}^{z_{max}} n_A^z + 2 \sum_{z=0}^1 n_{A_2}^z + \sum_{B \neq A} \sum_{z=0}^1 n_{AB}^z.$$

neutrality:
$$n_e = \sum_A \sum_{z=1}^{z_{max}} z n_A^z.$$

n_A = number density of element A

m_A = atomic mass

$$\rho_{tot} = \sum_A n_A m_A$$



Methods of calibration-free measurements

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LTE plasma of M elements $\Rightarrow M + 1$ parameters

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$\Leftrightarrow C_A$ of $M-1$ elements, n_e and T

Emission coeff. $\epsilon_{ul} = A_{ul} \frac{h\nu}{4\pi} n_u$

Boltzmann $n_u = n \frac{g_u}{Q(T)} e^{-E_u/kT}$

\Rightarrow measurement of $M + 1$ lines

$$n_A = \sum_{z=0}^{z_{max}} n_A^z + 2 \sum_{z=0}^1 n_{A_2}^z + \sum_{B \neq A} \sum_{z=0}^1 n_{AB}^z.$$

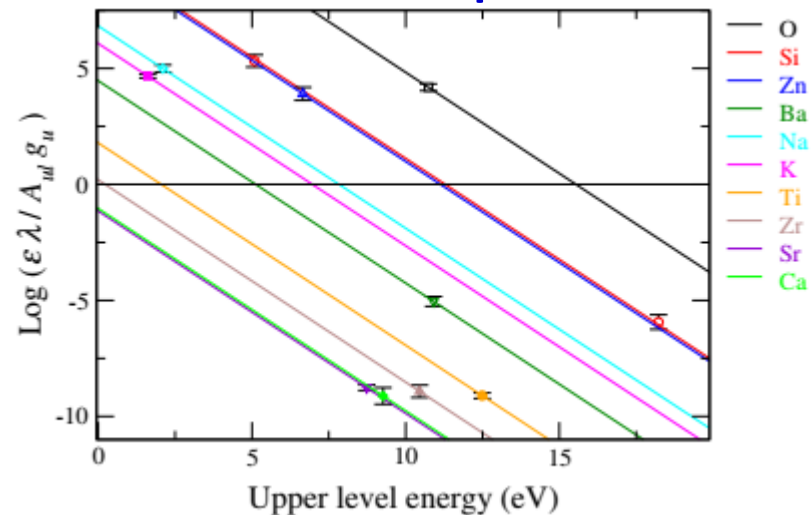
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$$\rho_{tot} = \sum_A n_A m_A$$

Boltzmann plot



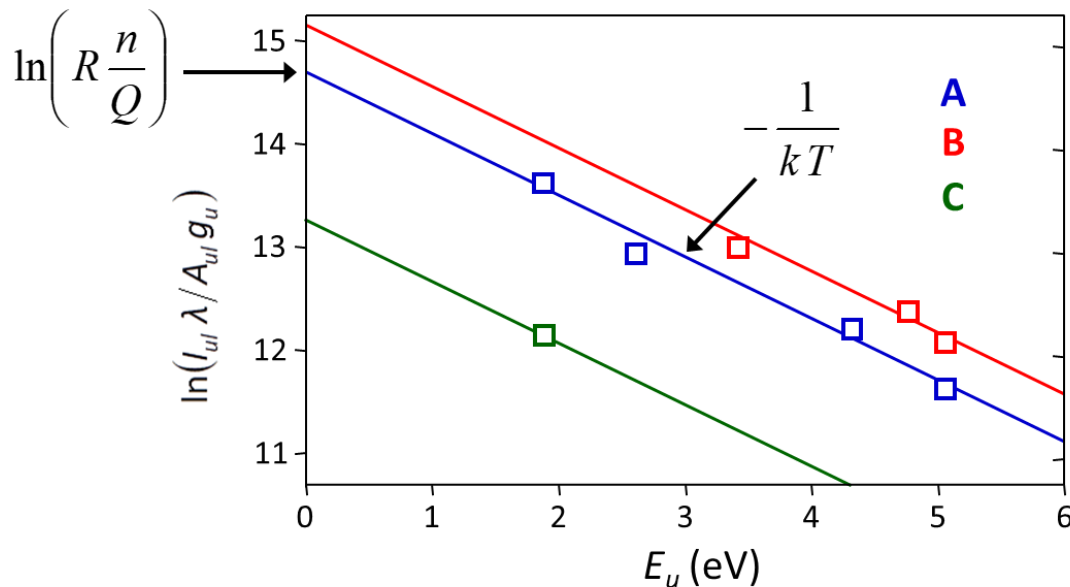
Methods of calibration-free measurements

First approach, *Ciucci et al. Appl. Spectrosc. 1999* \Rightarrow **multielemental Boltzmann plot**

moderate ionization $\Rightarrow n_i \ll n_n \Rightarrow n_n \cong n_A := n$

Emission coeff. $\varepsilon_{ul} = A_{ul} \frac{h\nu}{4\pi} n_u \Rightarrow I_{ul} \propto \varepsilon_{ul}$ **if optically thin**

Boltzmann $n_u = n \frac{g_u}{Q(T)} e^{-E_u/kT} \Rightarrow \ln\left(\frac{I_{ul} \lambda}{A_{ul} g_u}\right) = -\frac{E_u}{kT} + \ln\left(R \frac{n}{Q}\right)$



\Rightarrow **easy to implement**

\Rightarrow **big success**

\Rightarrow **low accuracy**

reduce errors

\Rightarrow **use of many lines**

\Rightarrow **error identification difficult**

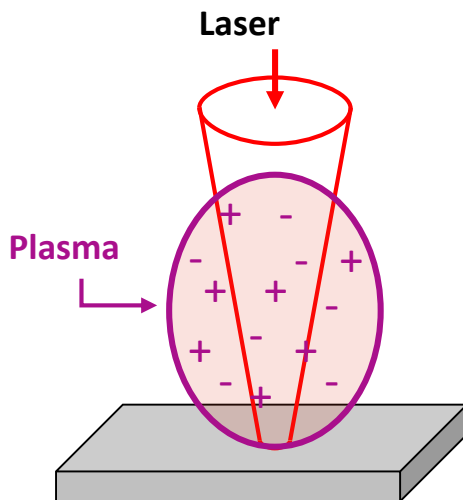
Methods of calibration-free measurements

First approach, *Ciucci et al. Appl. Spectrosc. 1999* ➡ **multielemental Boltzmann plot**

➡ **low accuracy**

⇒ amended methods with corrections

correction	need	feasibility
non-stoichiometric ablation	non	limited
failure of LTE	non	non
plasma non-uniformity	sometimes	limited
self-absorption	always	yes

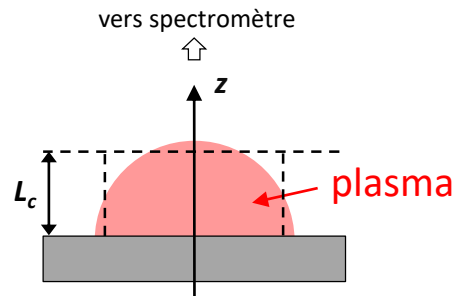
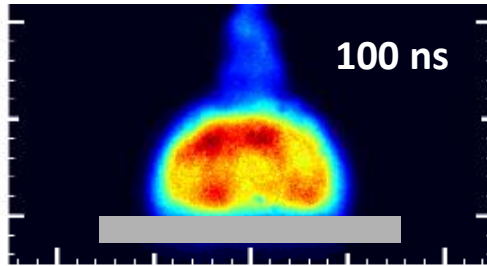


hypotheses :

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- local thermodynamic equilibrium
- plasma spatially uniform
- plasma optically thin

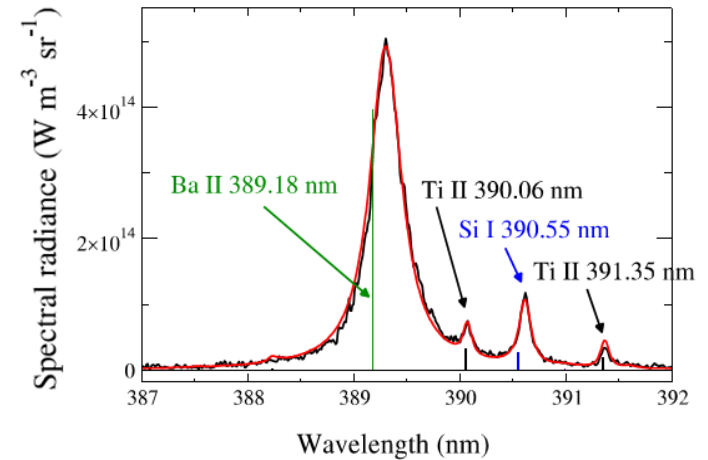
Methods of calibration-free measurements

Methods based on spectra simulation



$$\alpha_{line}(\lambda) = \pi r_0 \lambda^2 f_{lu} n_l P(\lambda_0, \lambda) (1 - e^{-hc/\lambda kT})$$

Doppler and Stark broadening



analytical solution of radiation transfer equation
Hermann et al. J. Appl. Phys 1998

$$\Rightarrow \text{Spectral radiance } B_\lambda = U_\lambda (1 - e^{-\tau})$$

U_λ = blackbody spectral radiance

τ = optical thickness = $\int \alpha(\lambda, z) dz = \alpha(\lambda) L$

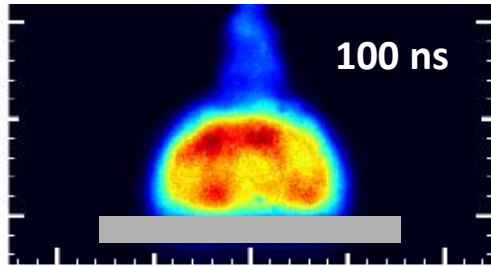
α = absorption coefficient = $\sum_i \alpha_{line}^{(i)} + \alpha_{ion} + \alpha_{IB}$

L = plasma diameter along line of sight

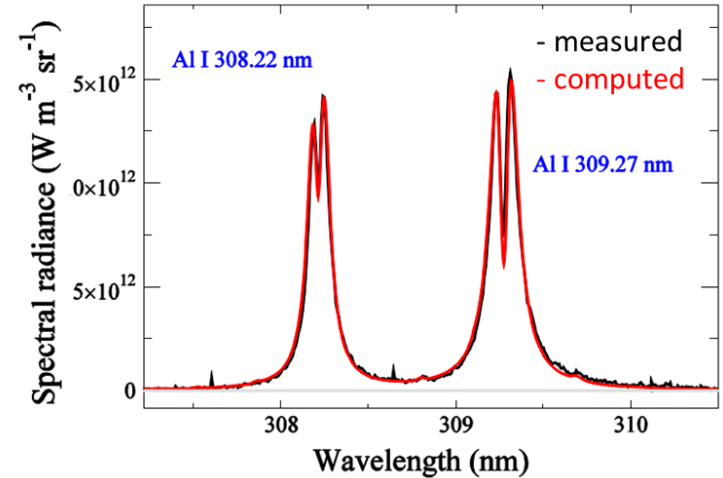
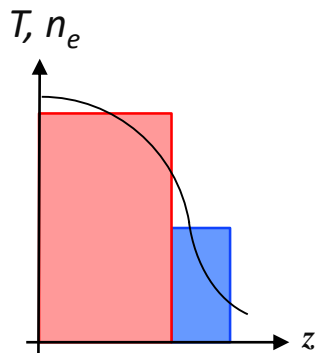
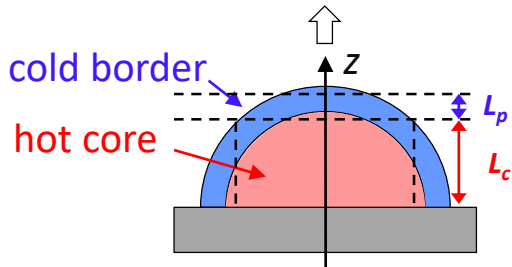
fast calculation

Methods of calibration-free measurements

Methods based on spectra simulation



to spectrometer



analytical solution of radiation transfer equation
Hermann et al. J. Appl. Phys 1998

spectral radiance :

$$B = U_C \left(1 - e^{-\alpha_C L_C}\right) e^{-\alpha_P L_P} + U_P \left(1 - e^{-\alpha_P L_P}\right)$$

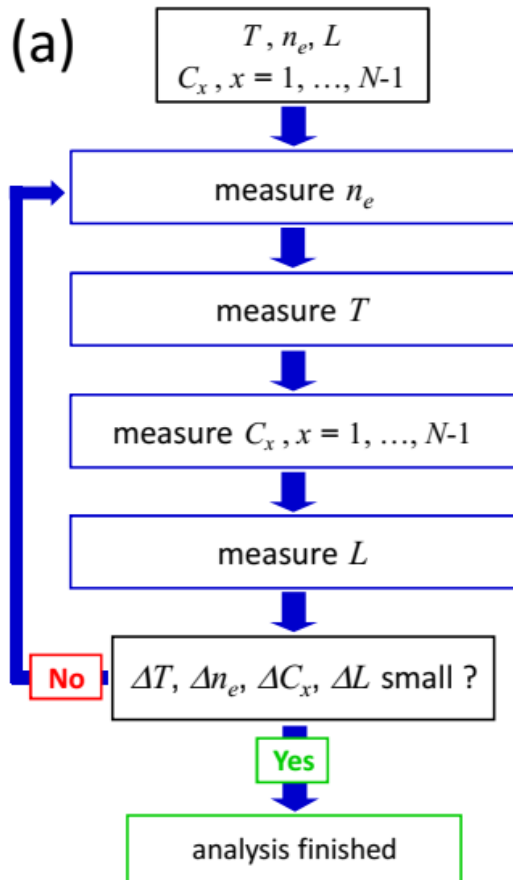
absorption coefficient :

$$\alpha(\lambda, T) = \pi r_0 \lambda^2 f_{lu} n_l P(\lambda_0, \lambda) \left(1 - e^{-hc/\lambda kT}\right)$$

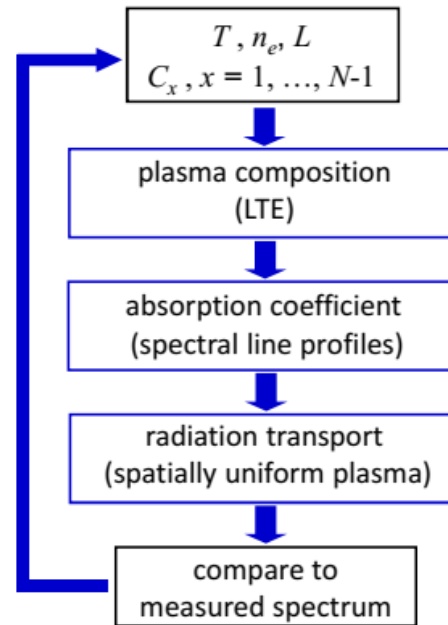
fast calculation

Methods of calibration-free measurements

Methods based on spectra simulation



(b) CF-LIBS method developed in LP3 US patent 8942927 B2 (2015)



CF-LIBS method developed in LP3



US patent 8942927 B2 (2015)

example : analysis of fused silica (SiO_2)

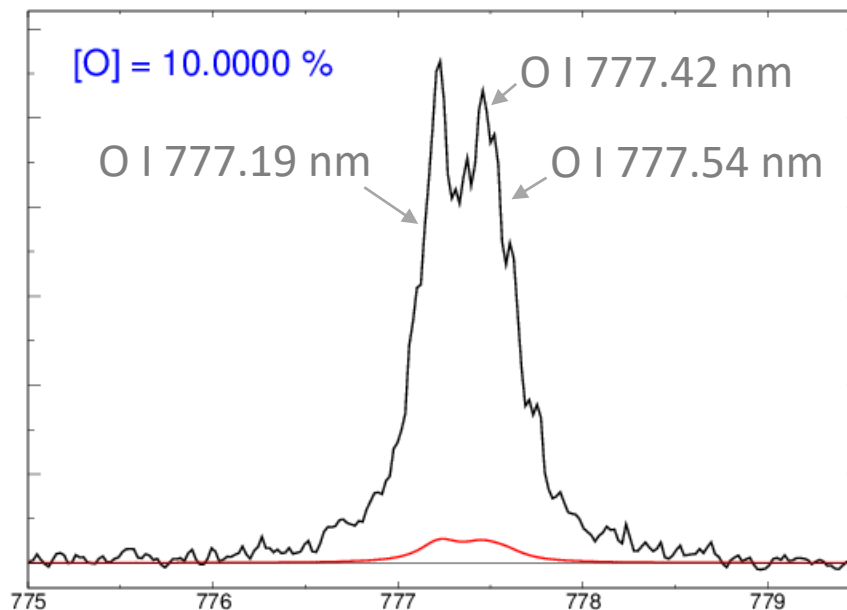
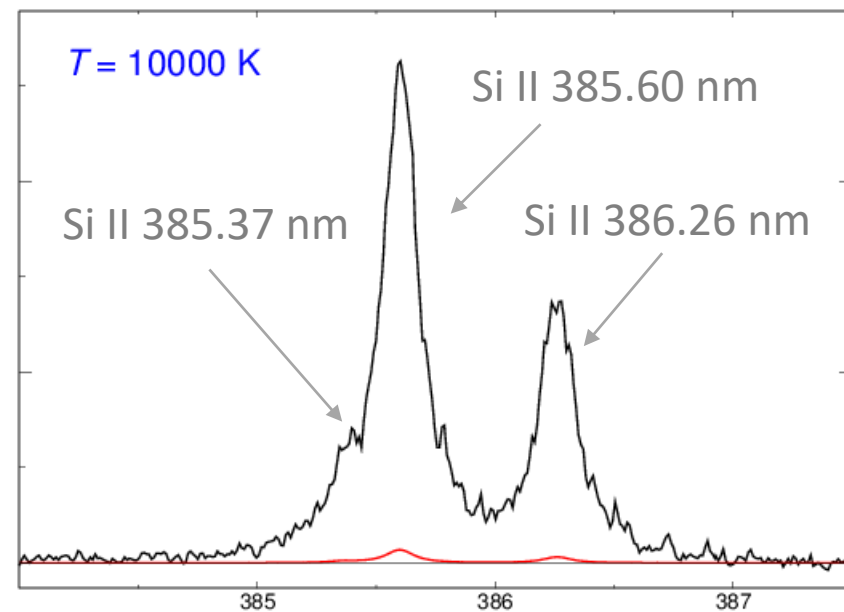
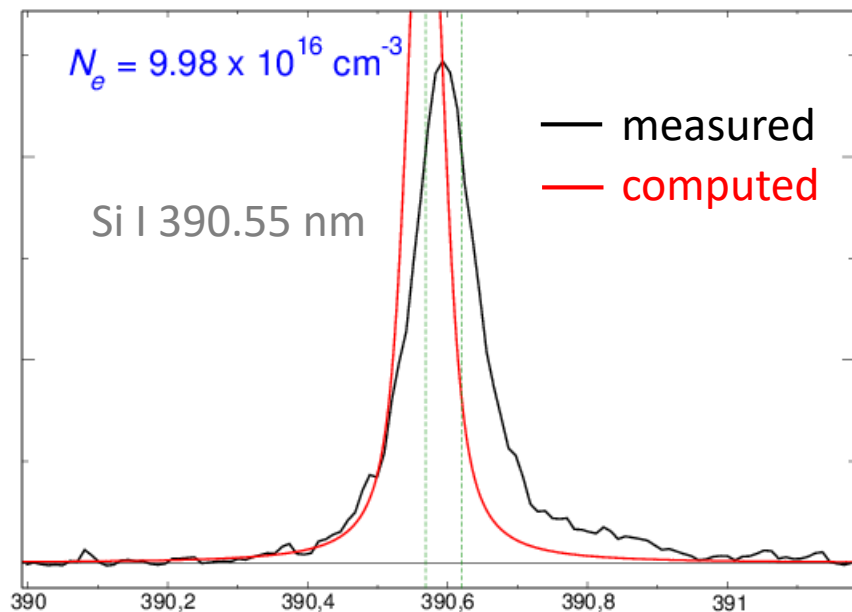
LTE plasma of M elements $\Rightarrow M + 1$ parameters

$\Leftrightarrow C_A$ of $M-1$ elements, n_e and T

$M = 2$ elements \Rightarrow **measurement of $M + 1$ lines**

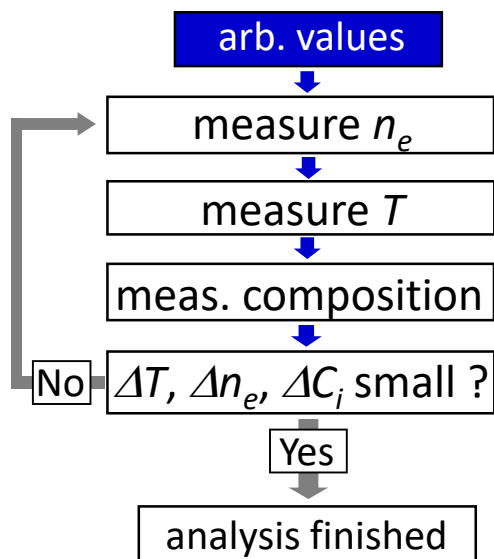
- n_e measurement
- T measurement
- composition measurement

analysis of fused silica

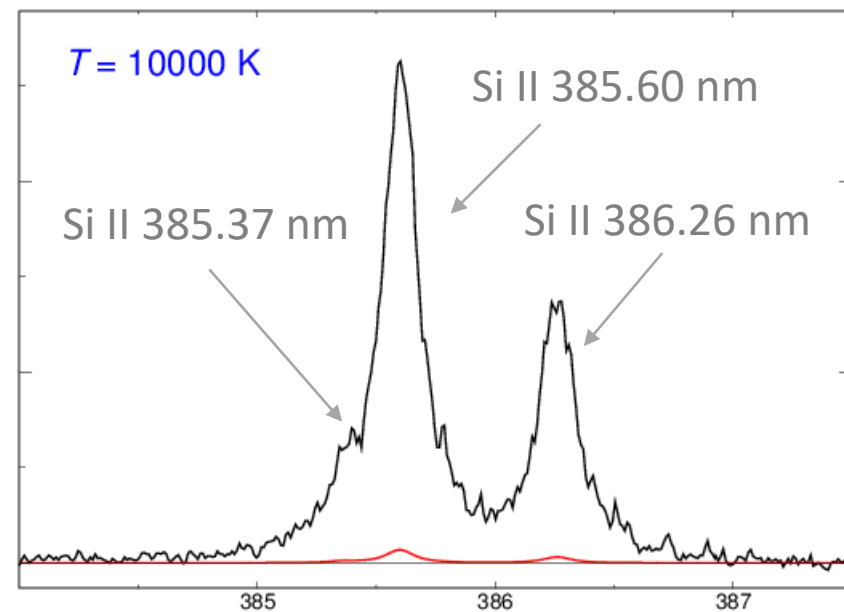
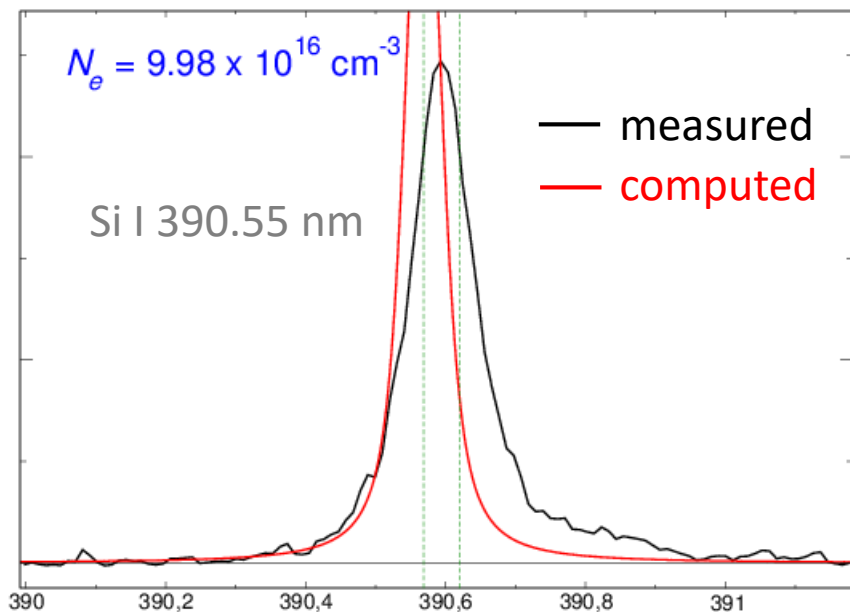


laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

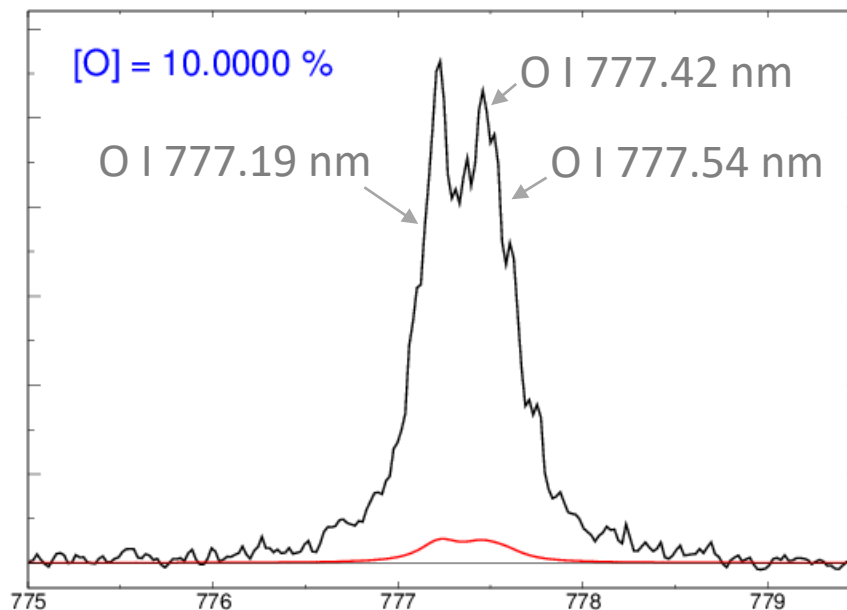
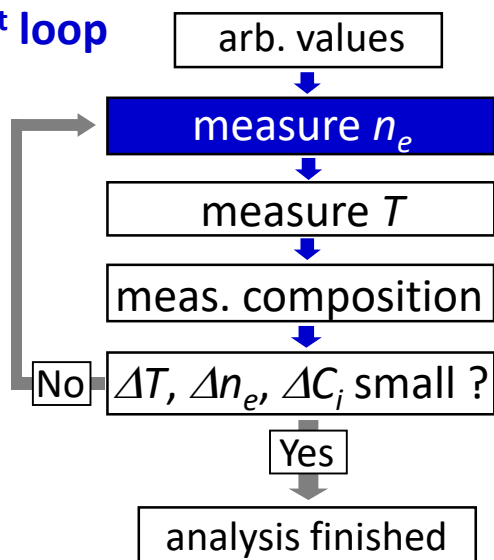
NIST data



analysis of fused silica



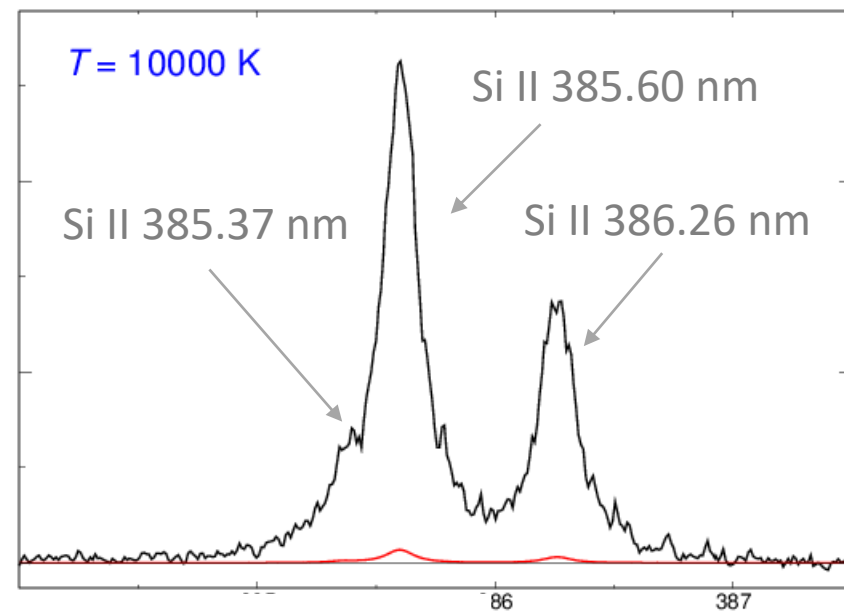
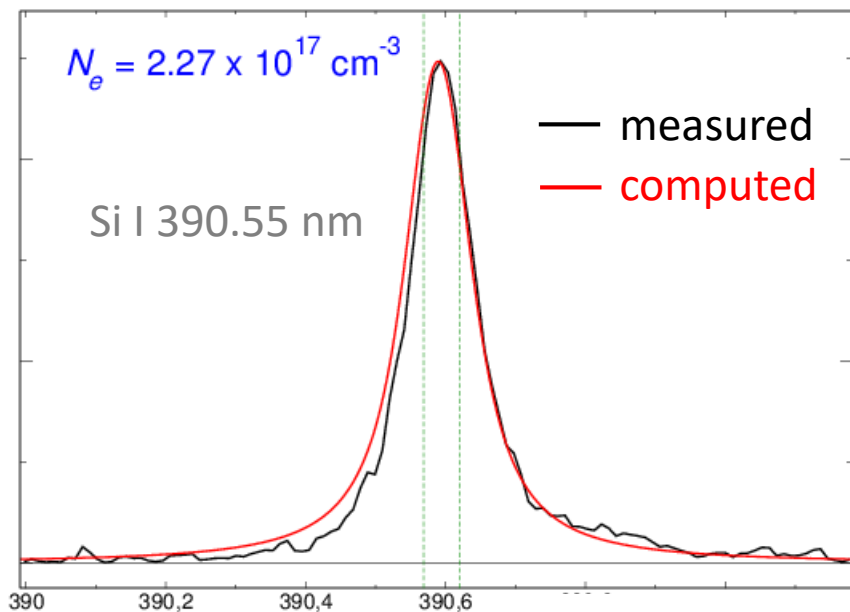
1st loop



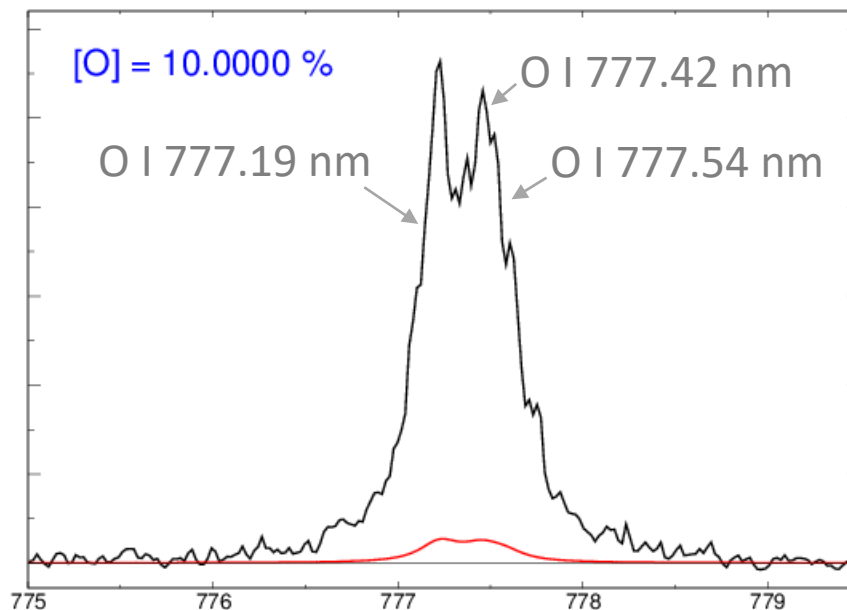
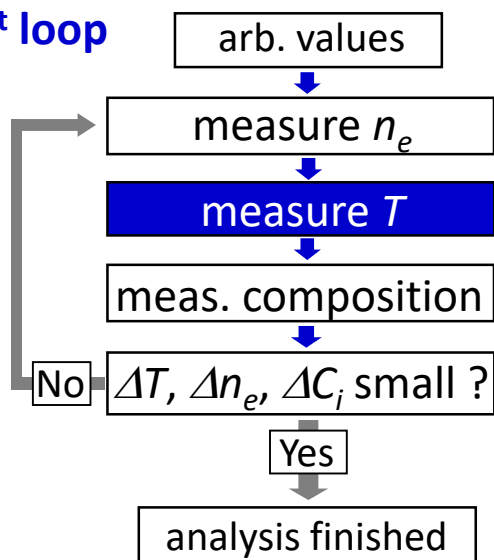
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



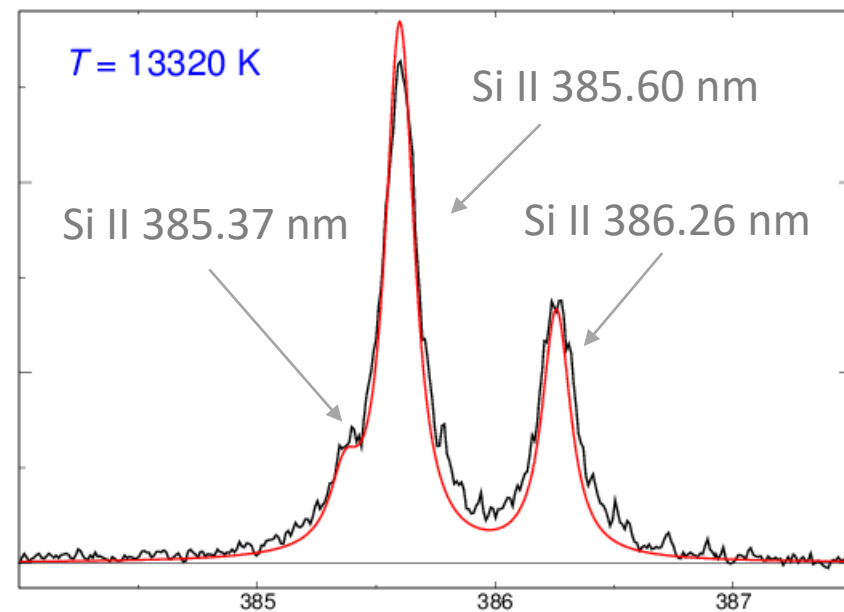
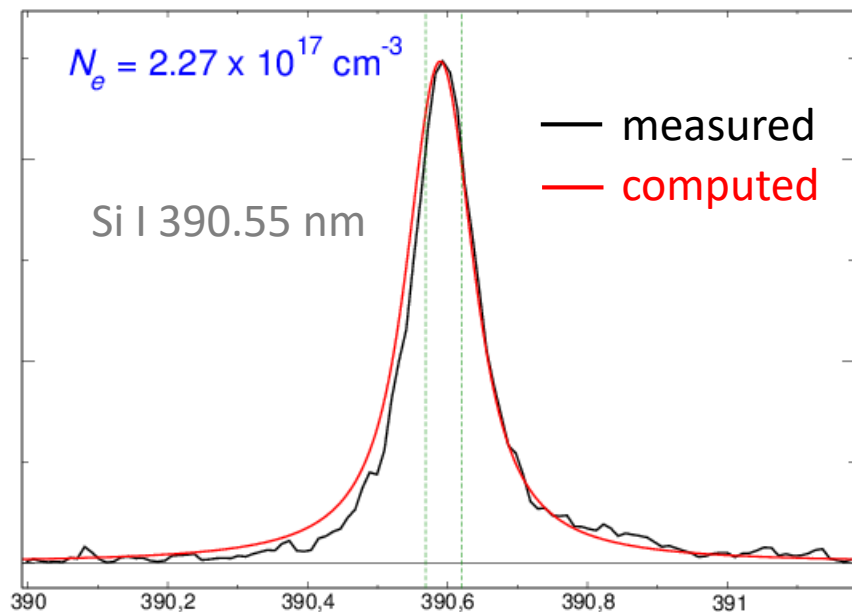
1st loop



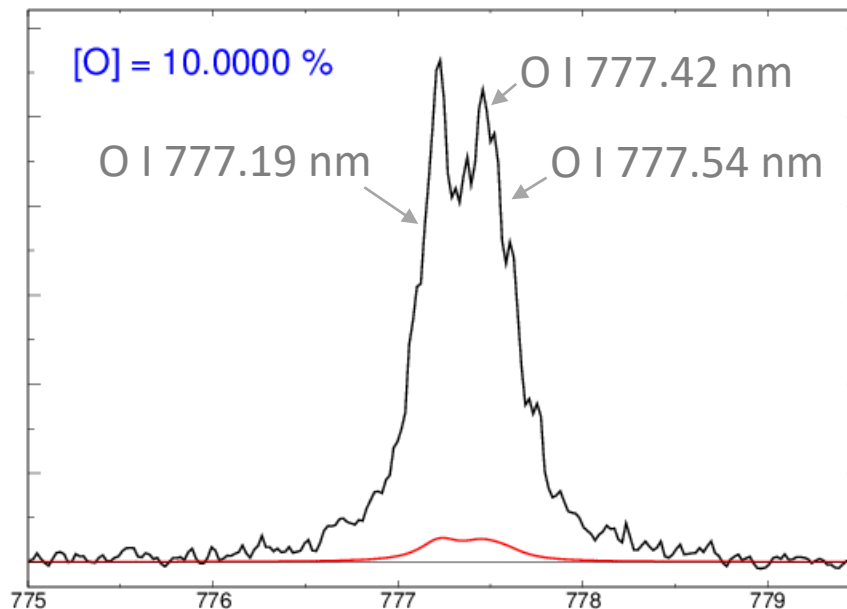
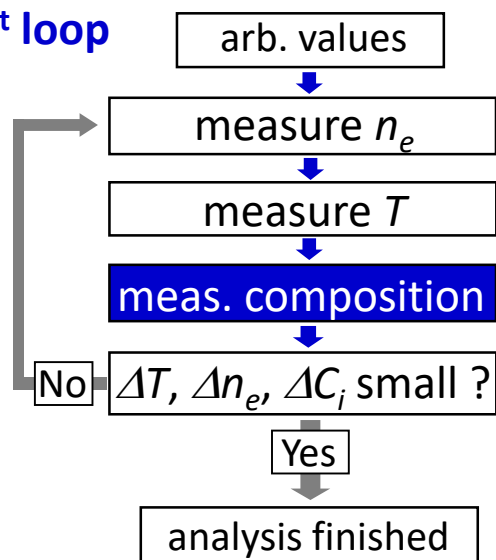
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



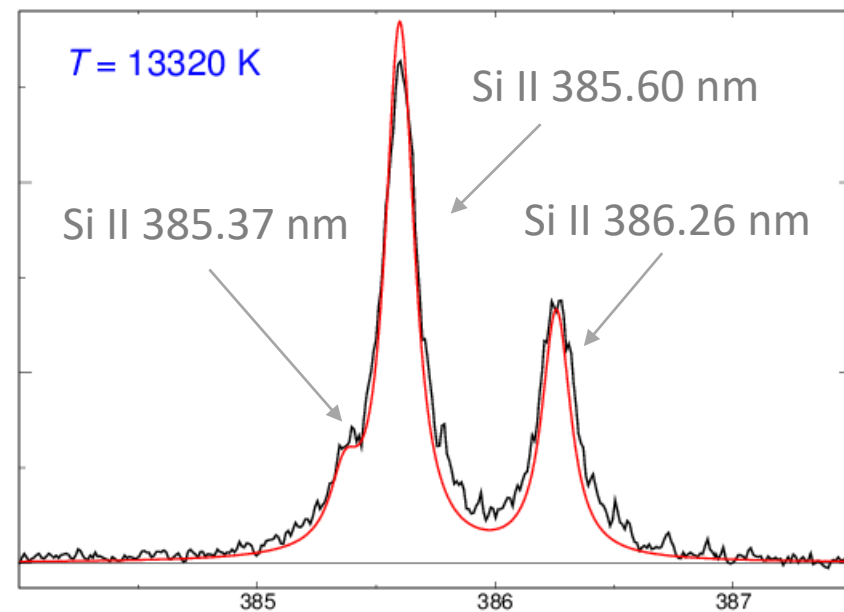
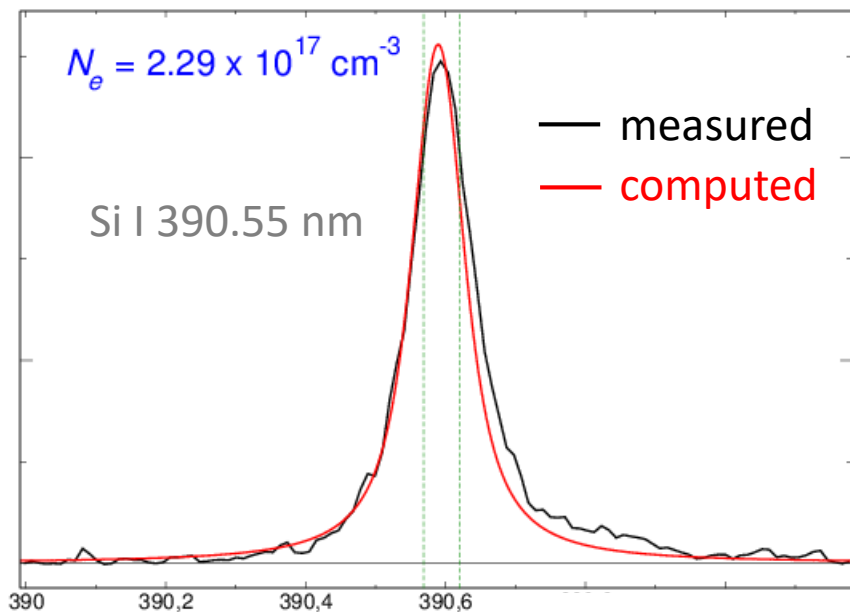
1st loop



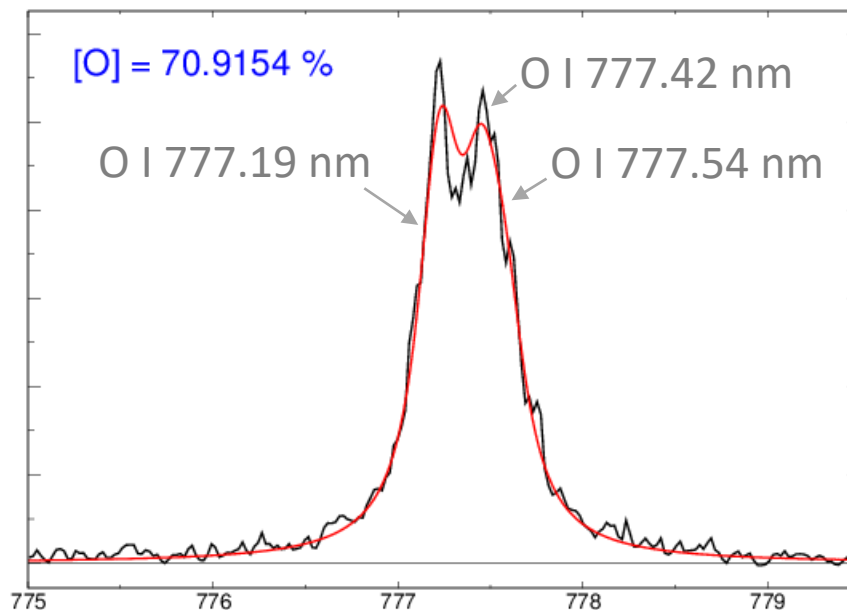
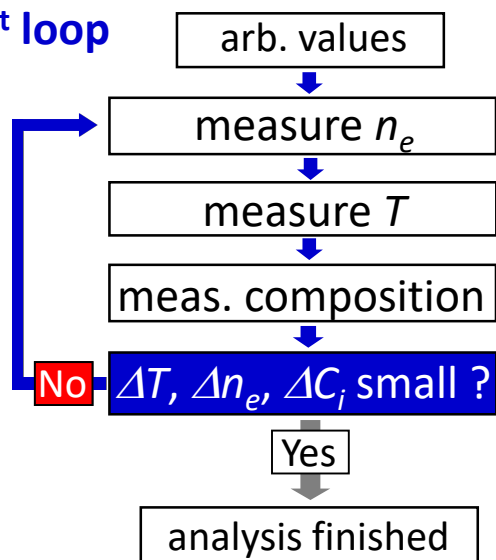
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



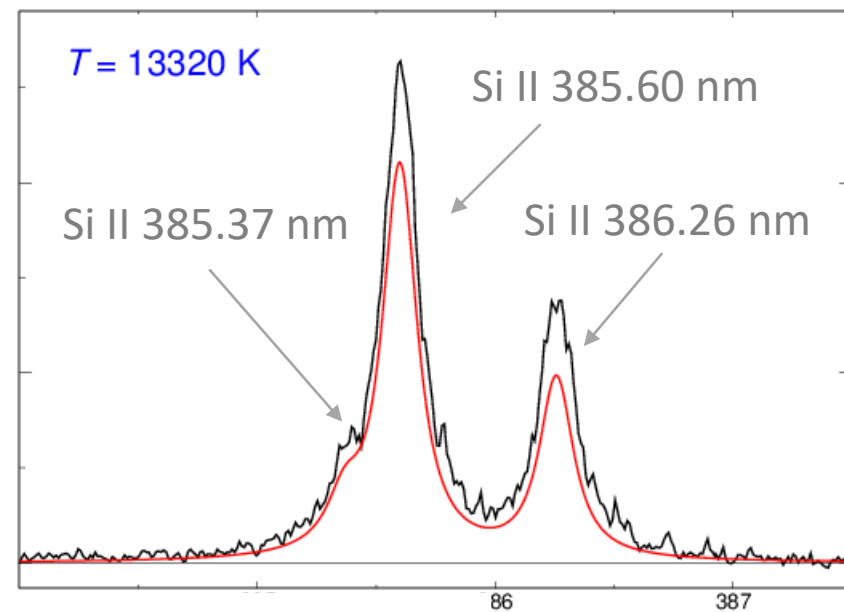
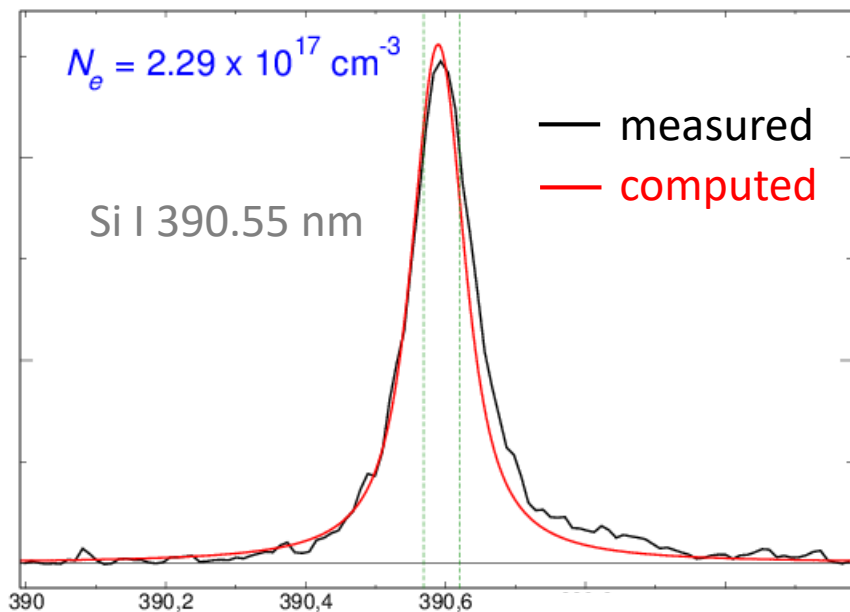
1st loop



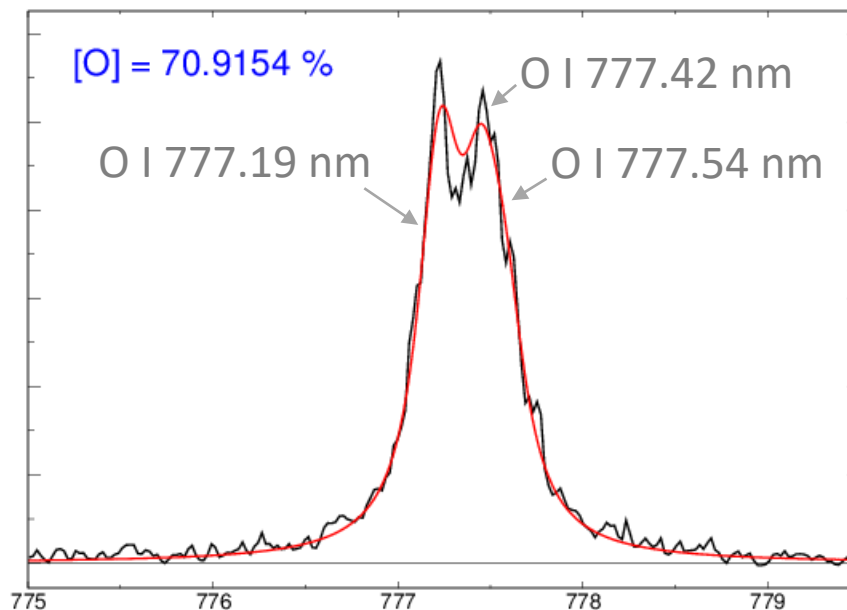
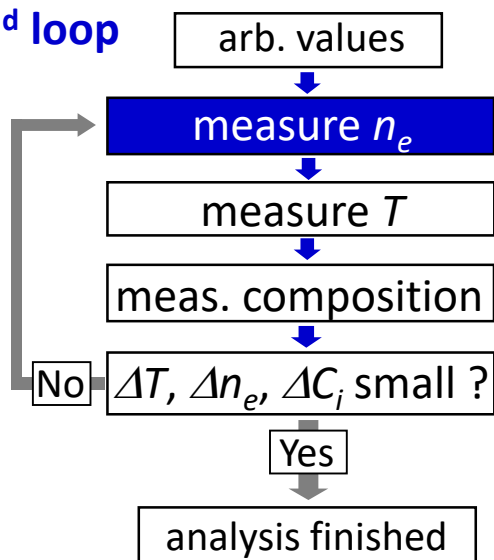
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



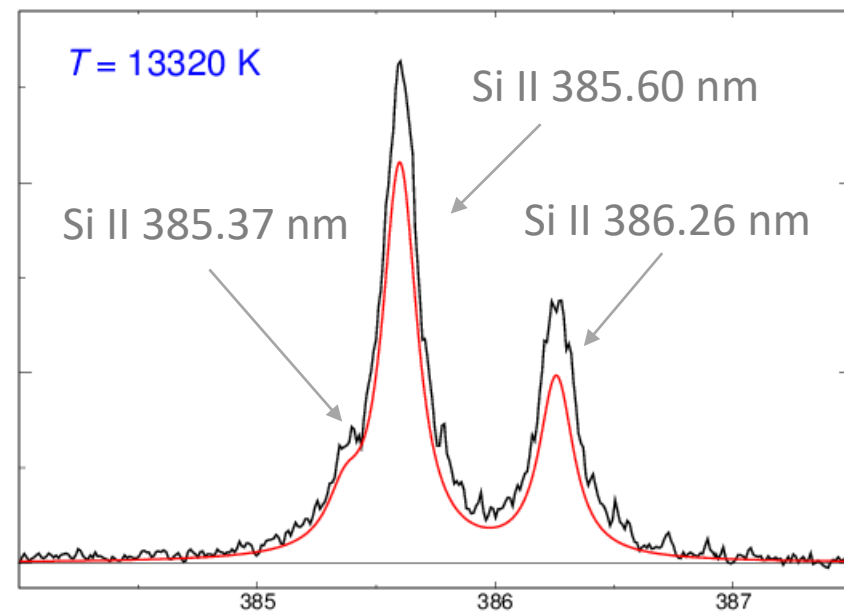
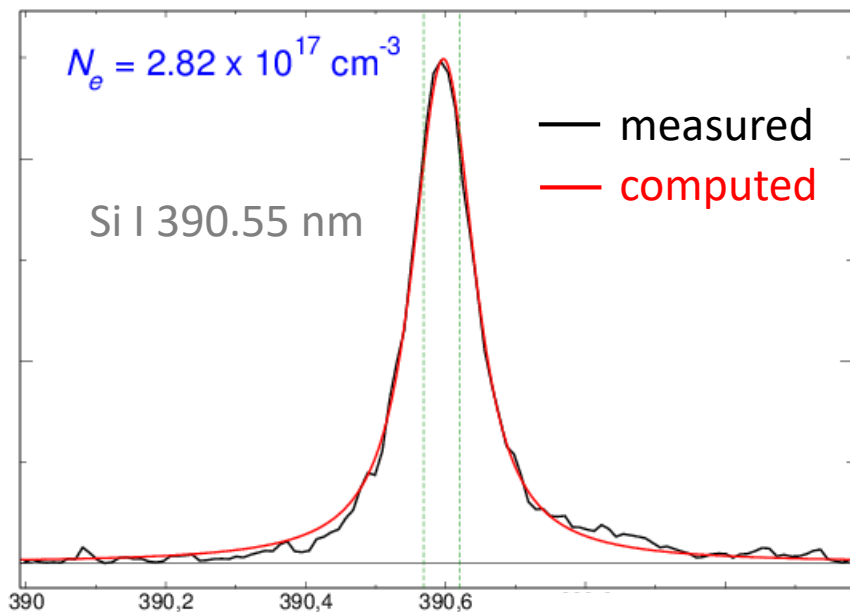
2nd loop



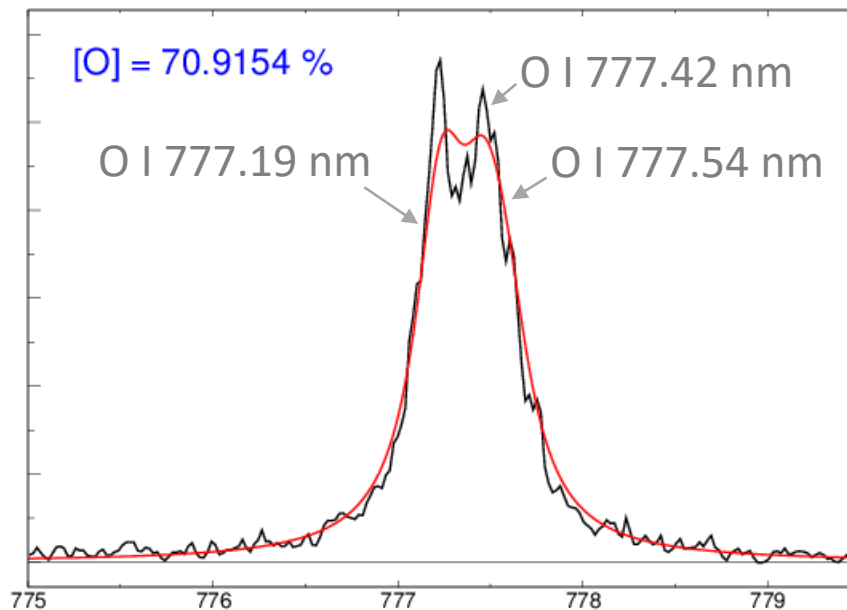
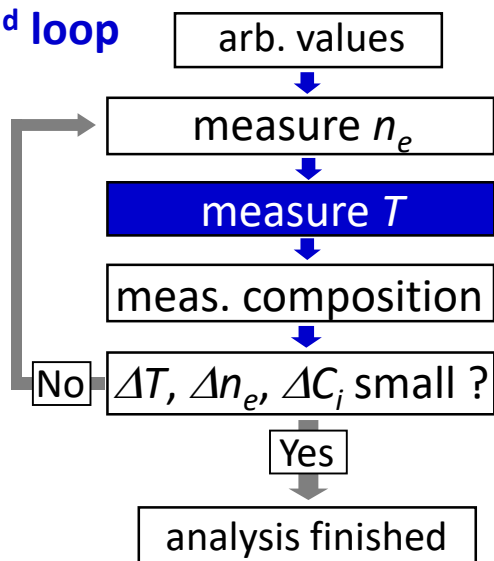
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



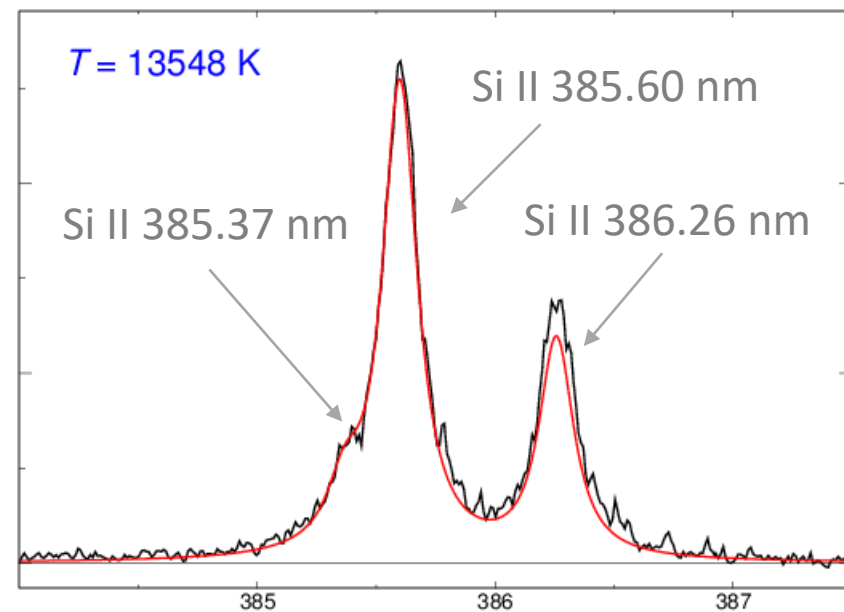
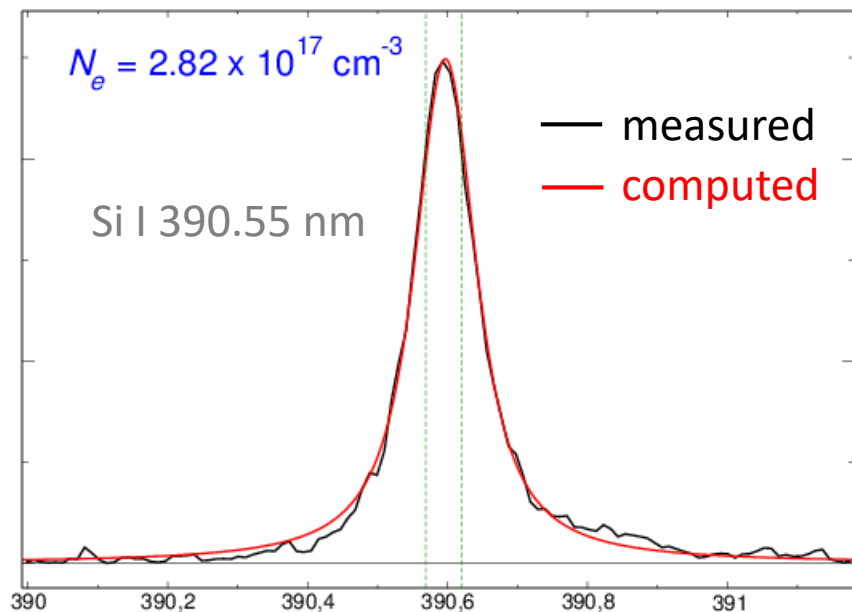
2nd loop



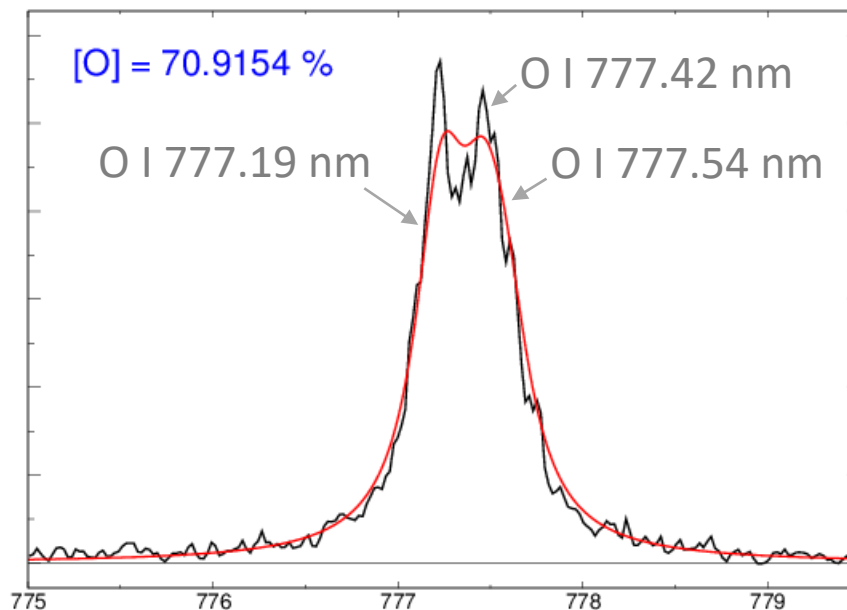
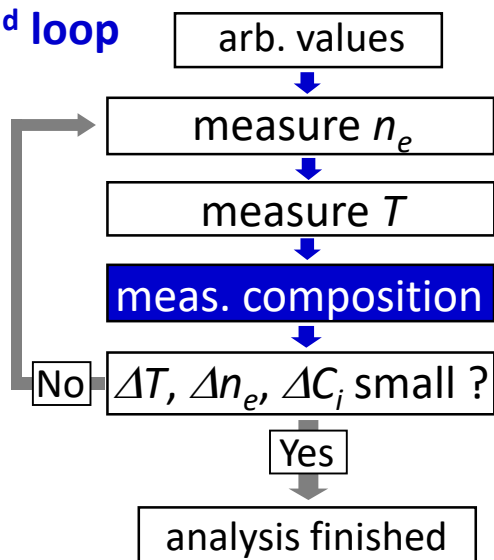
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



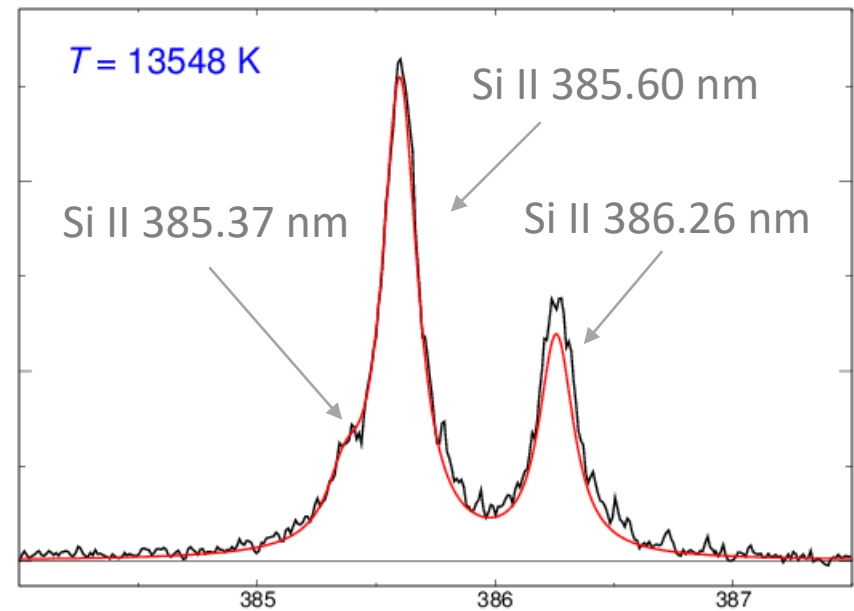
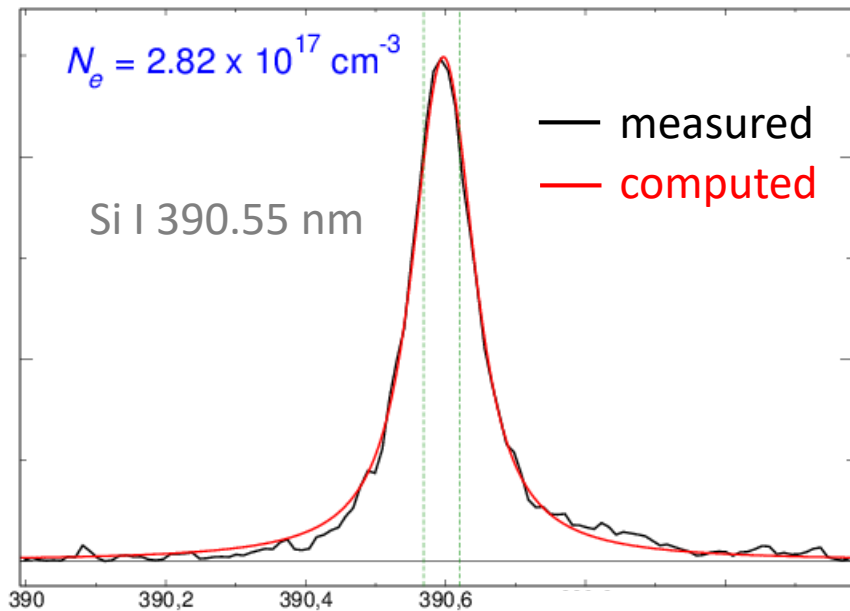
2nd loop



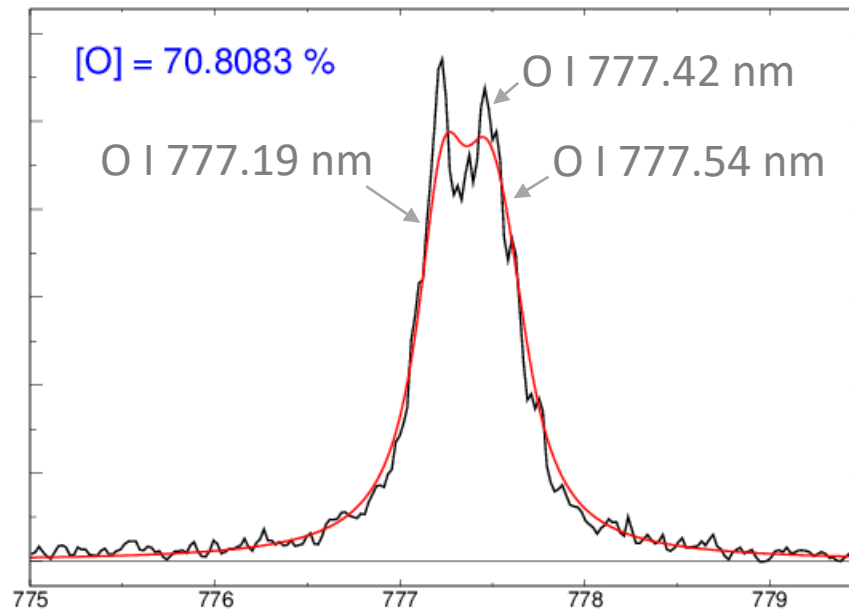
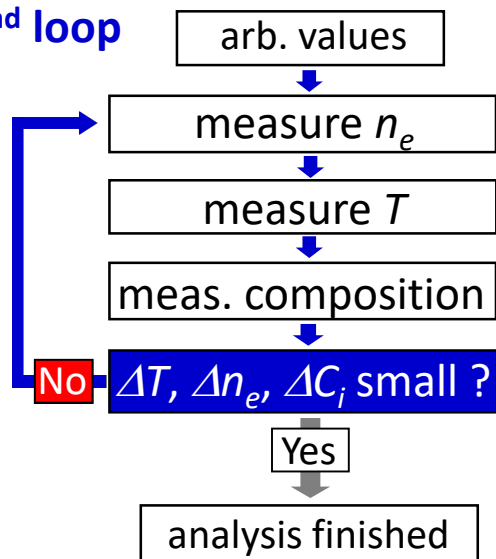
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



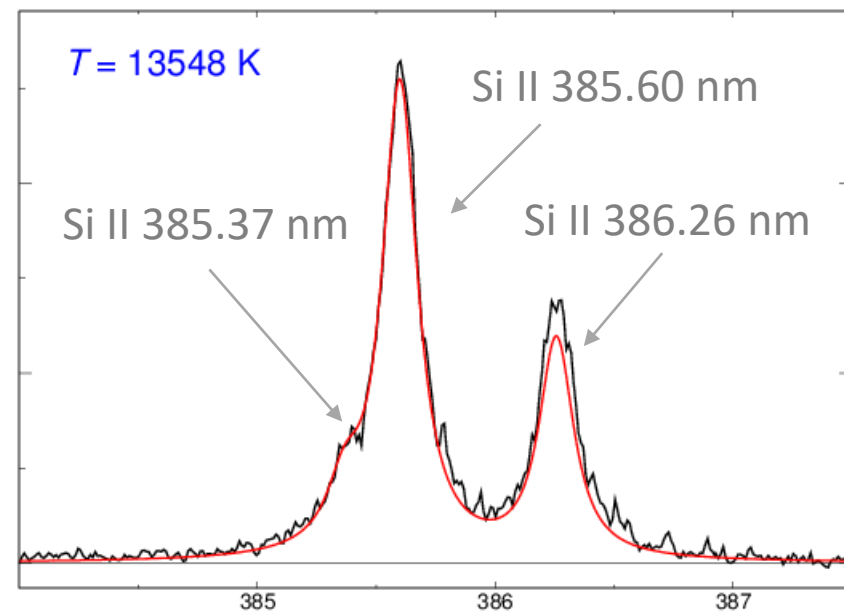
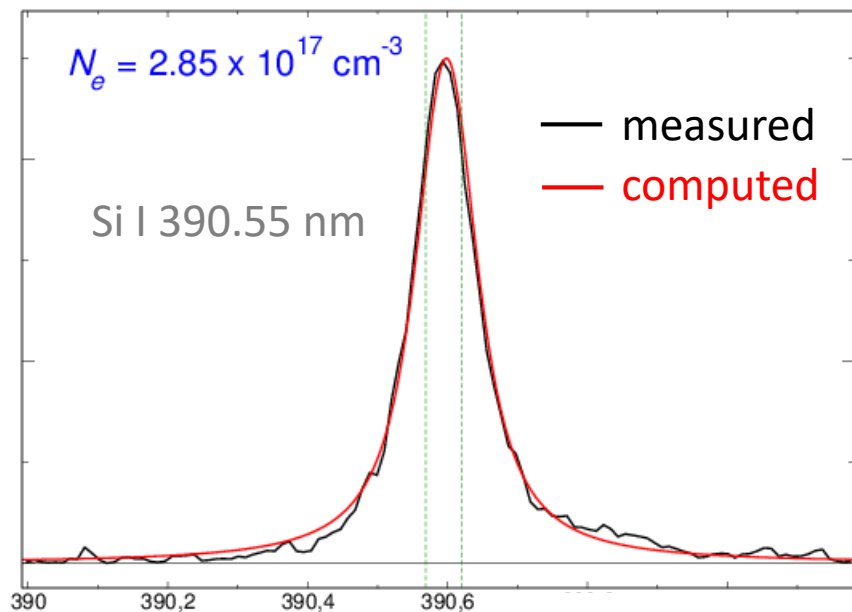
2nd loop



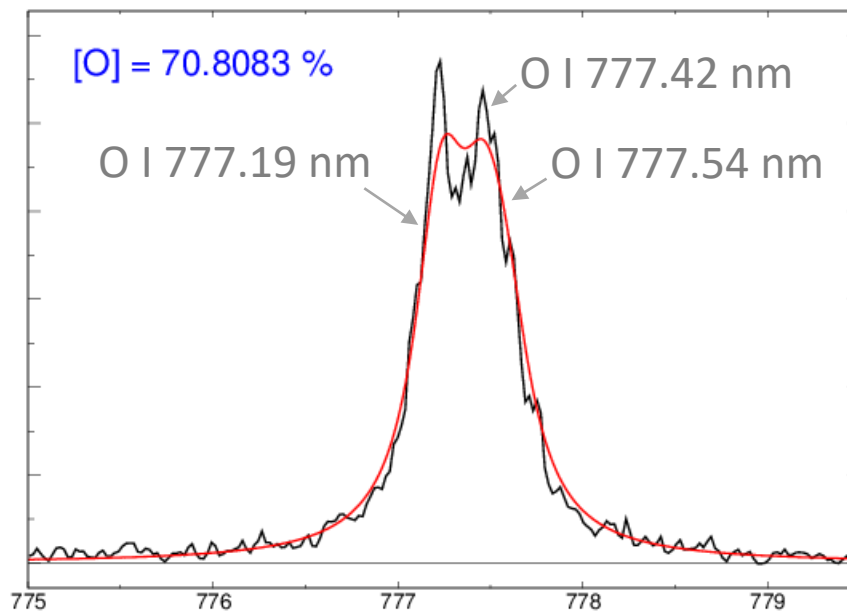
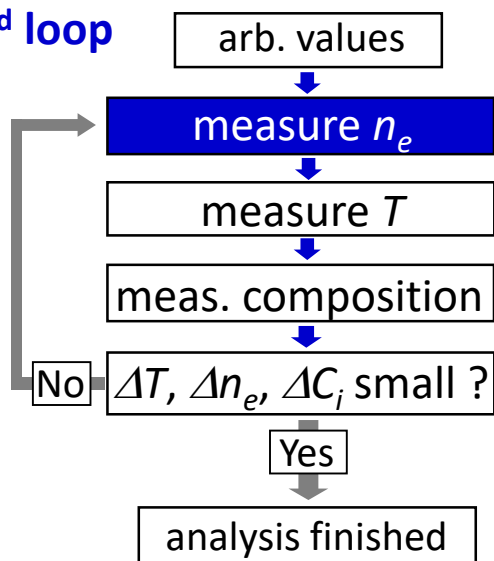
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



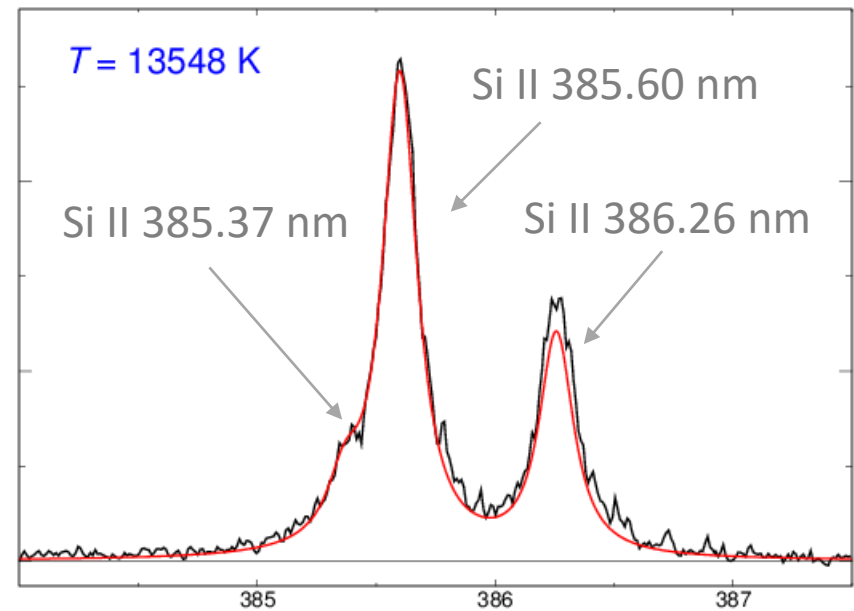
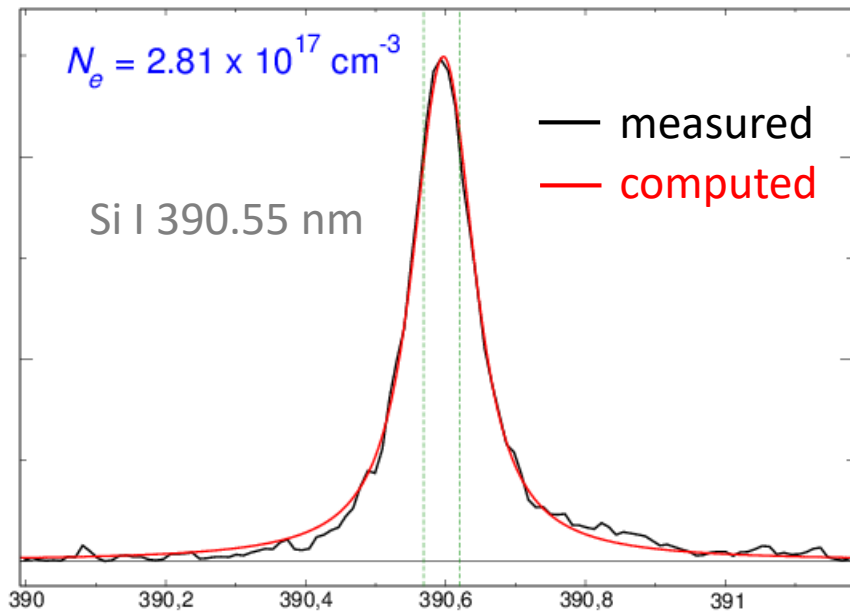
3rd loop



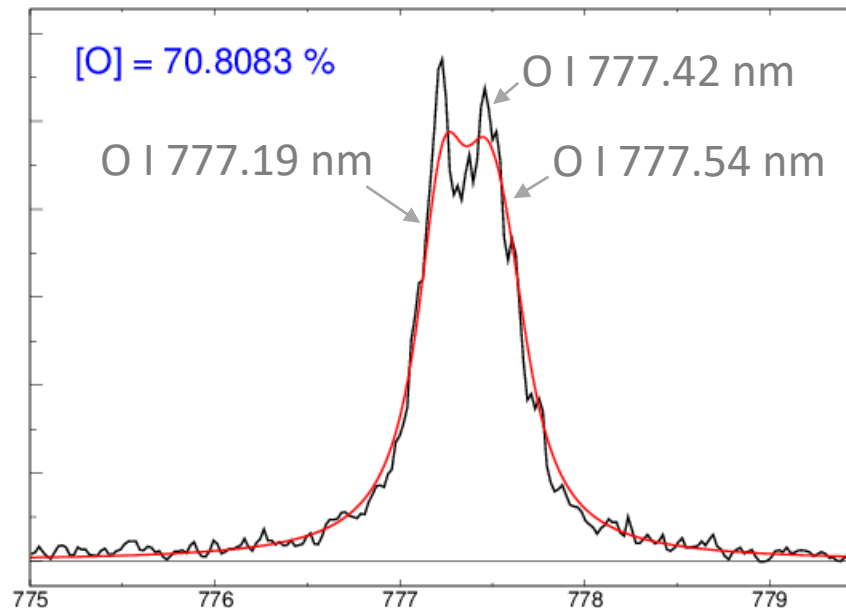
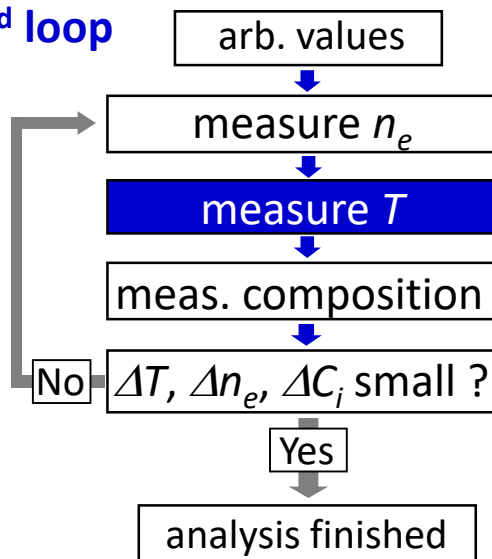
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



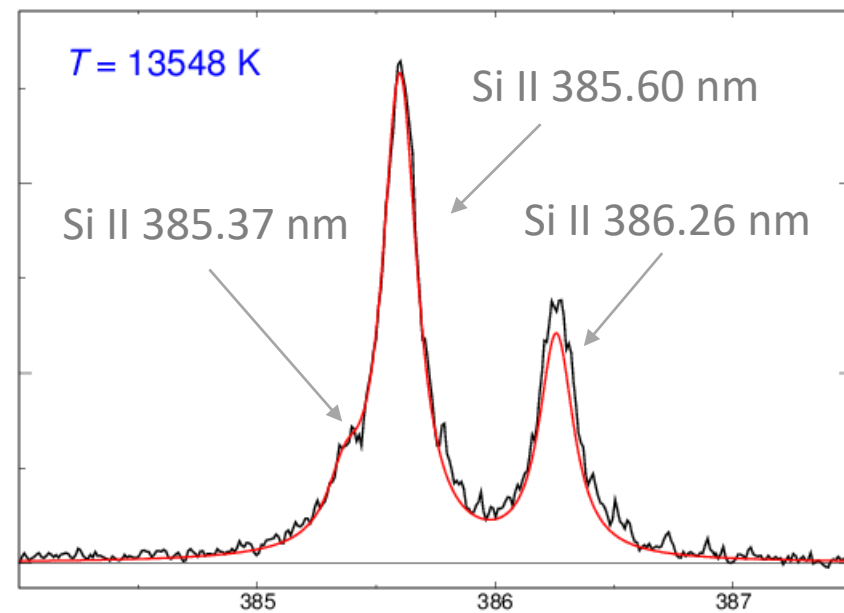
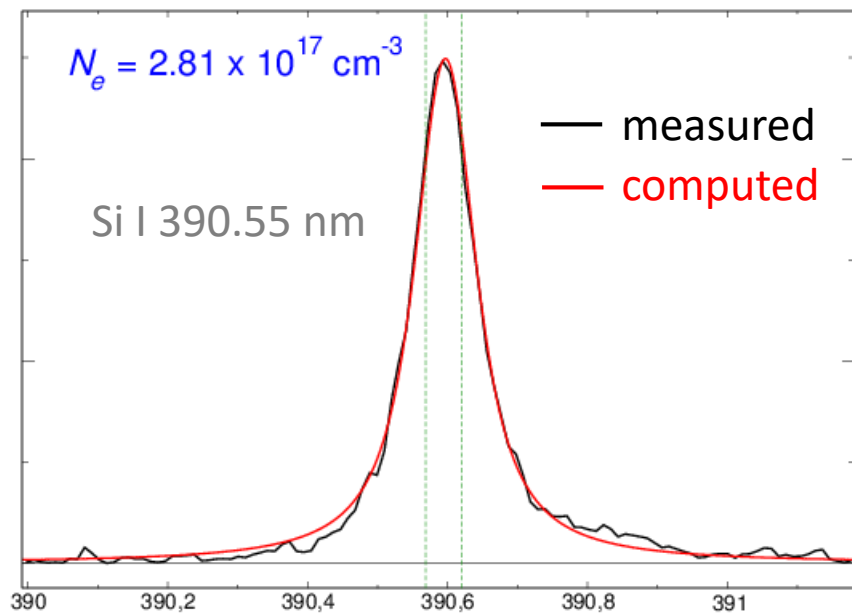
3rd loop



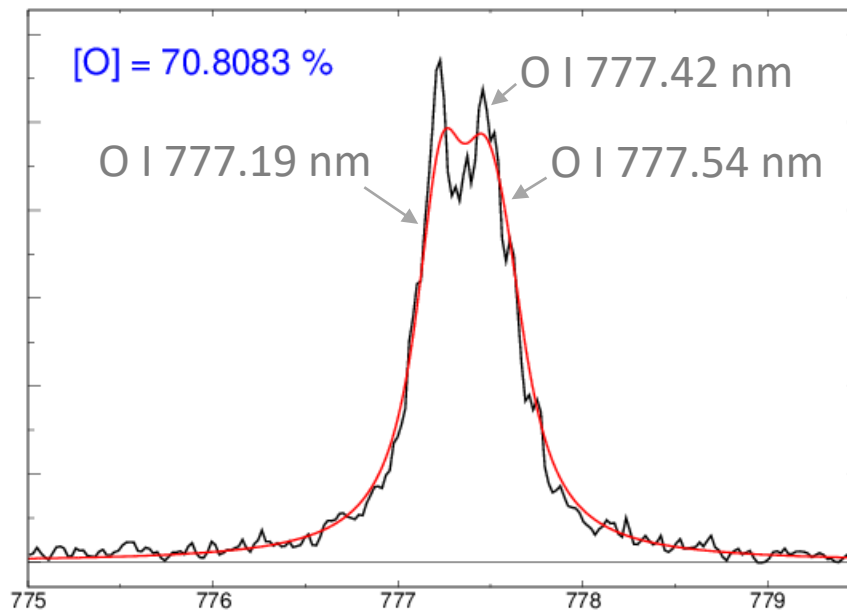
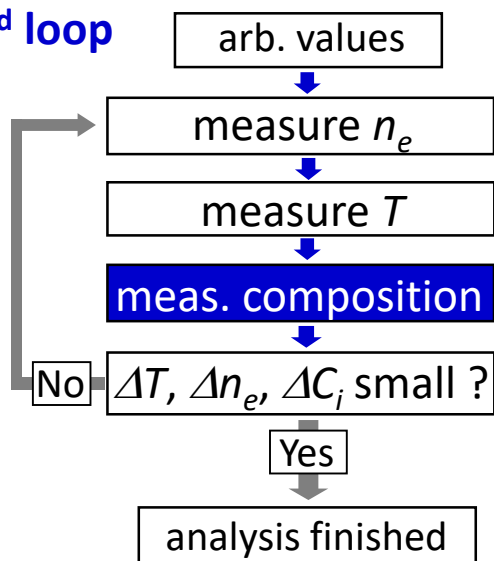
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



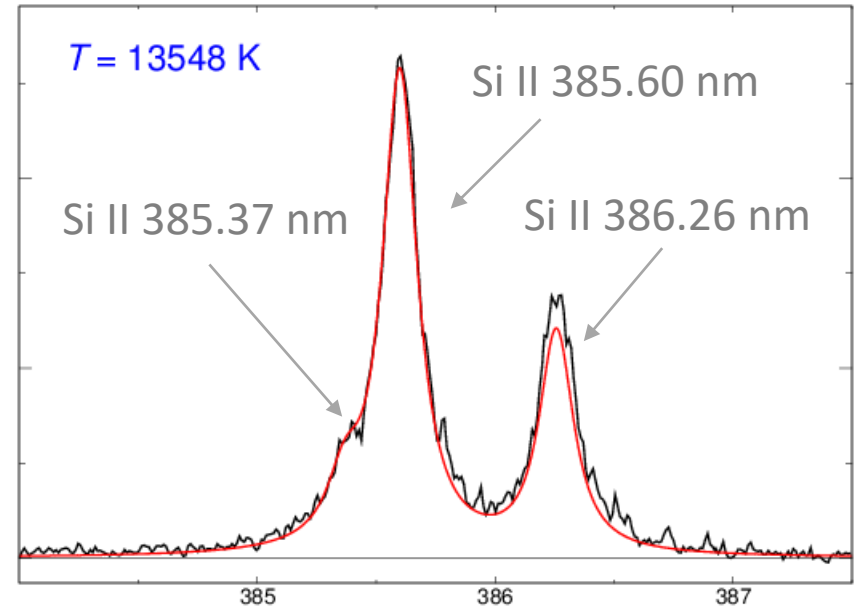
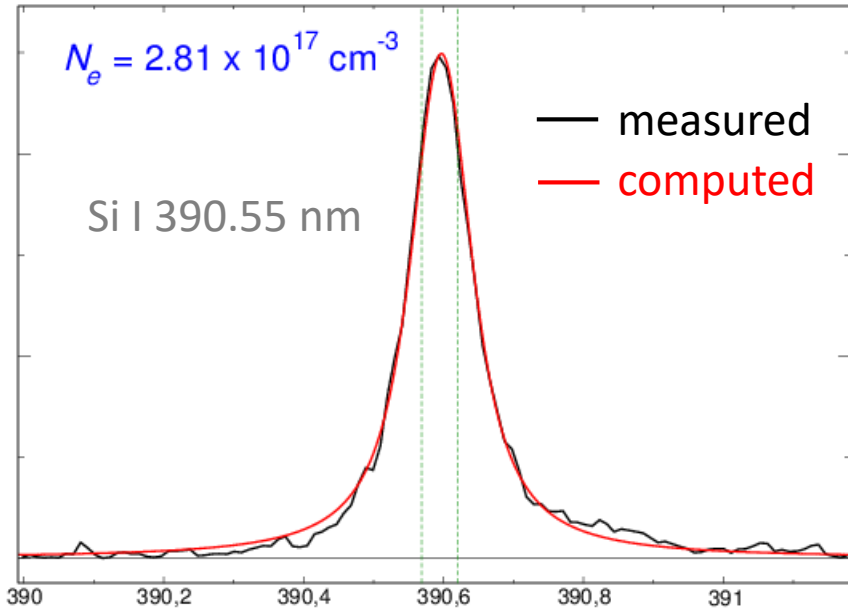
3rd loop



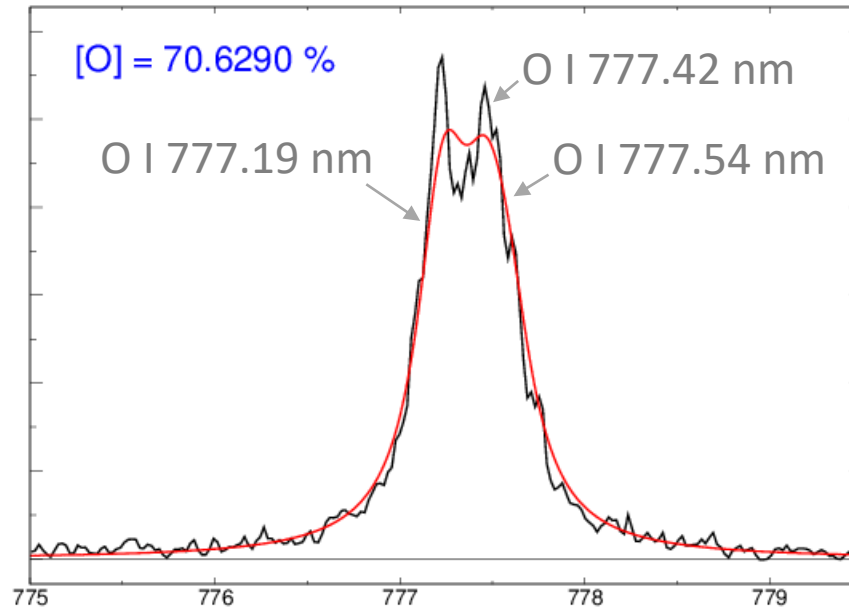
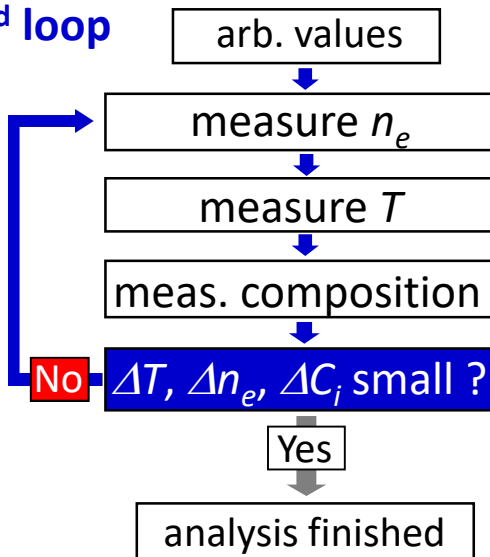
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



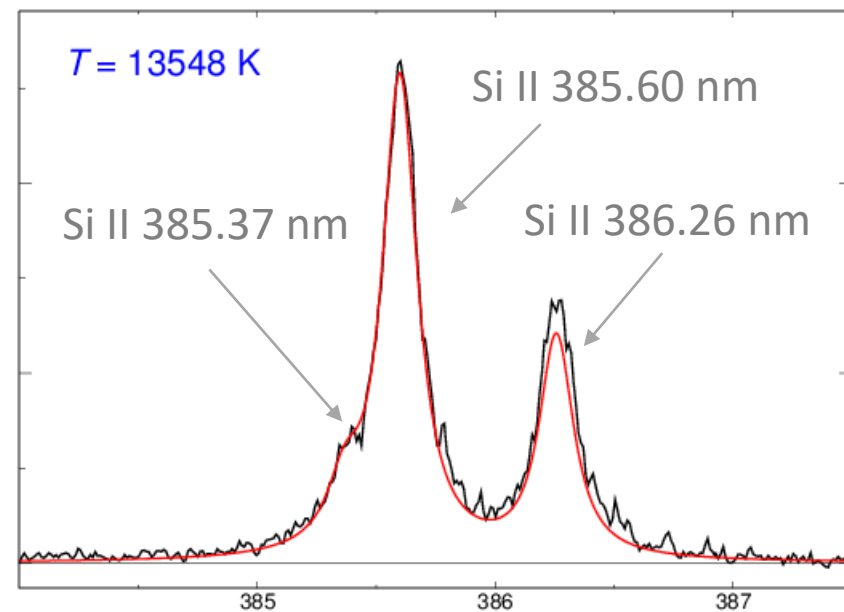
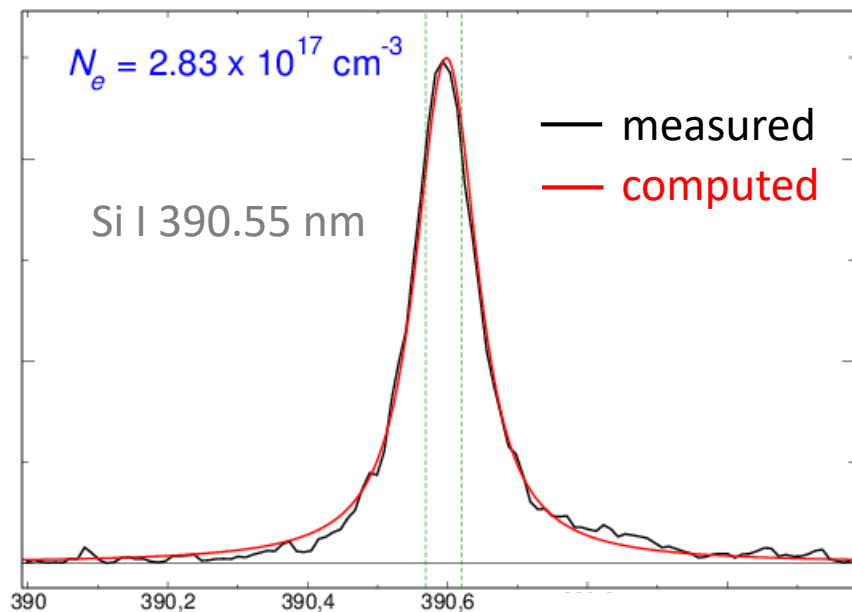
3rd loop



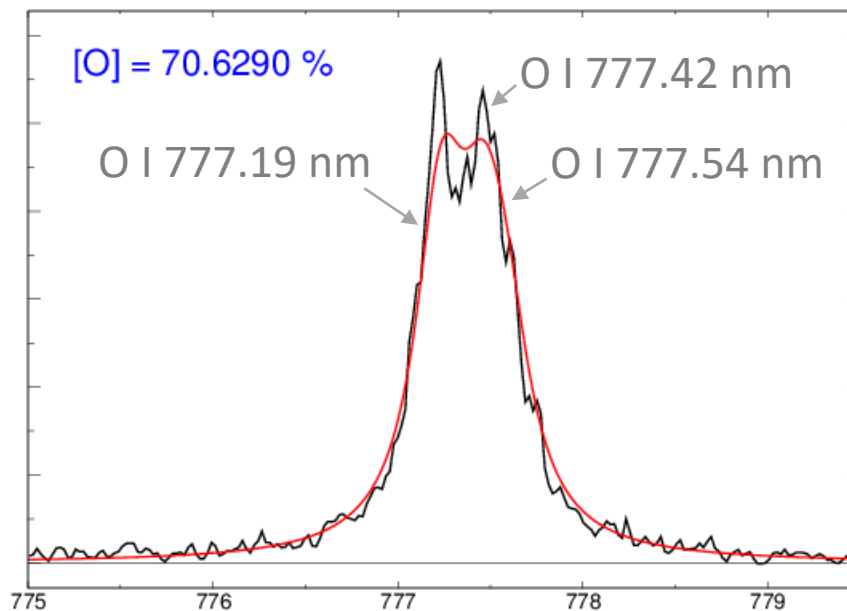
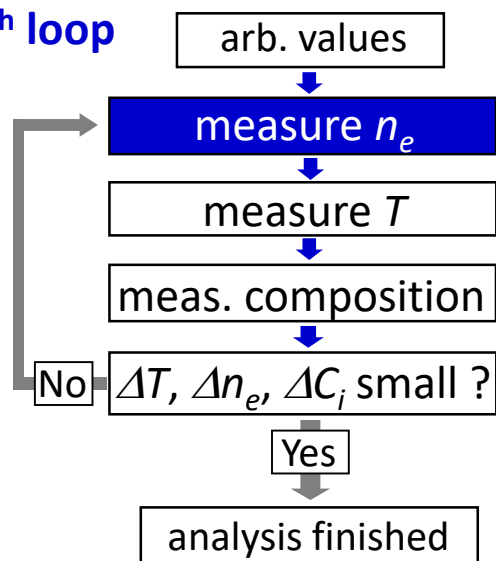
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



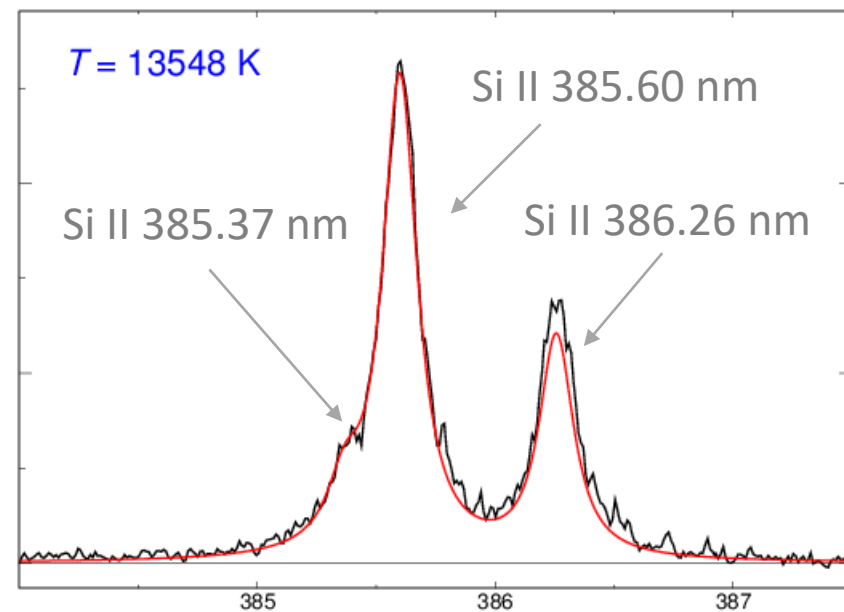
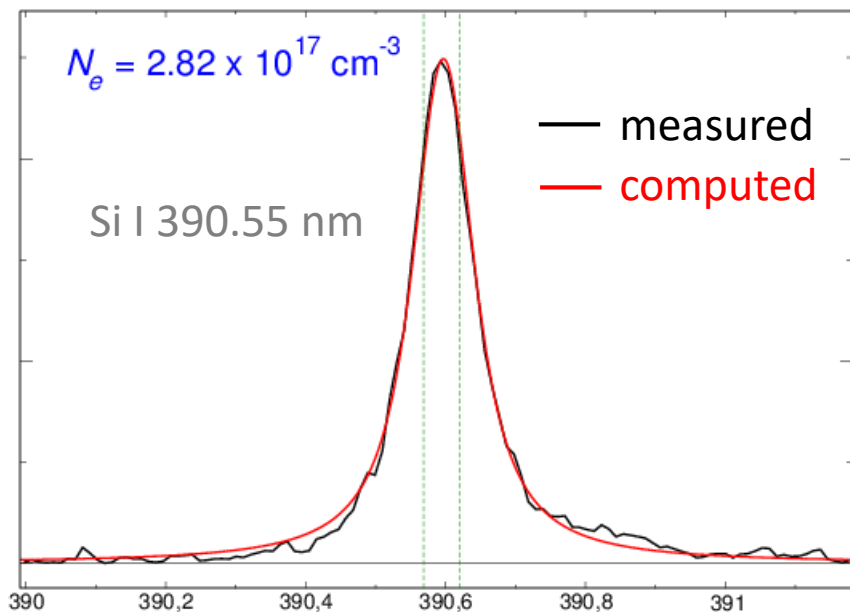
4th loop



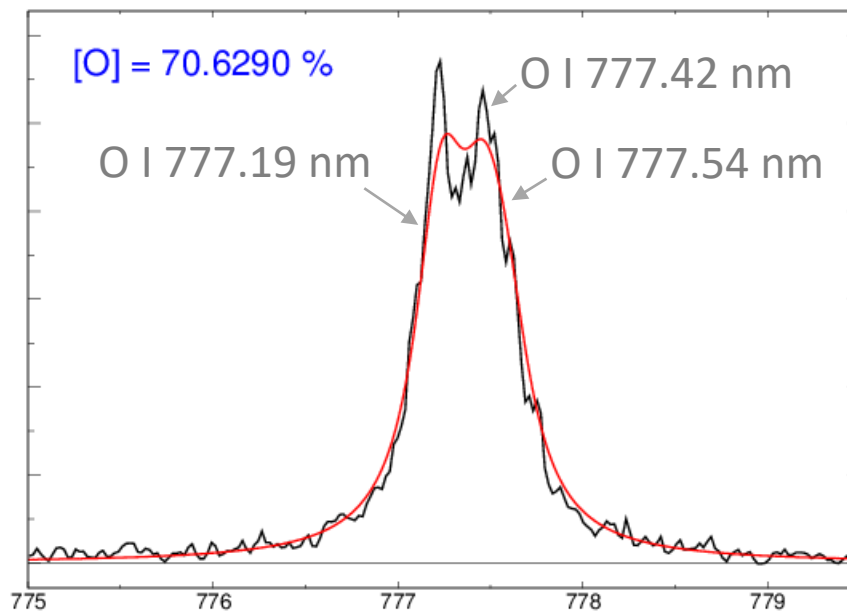
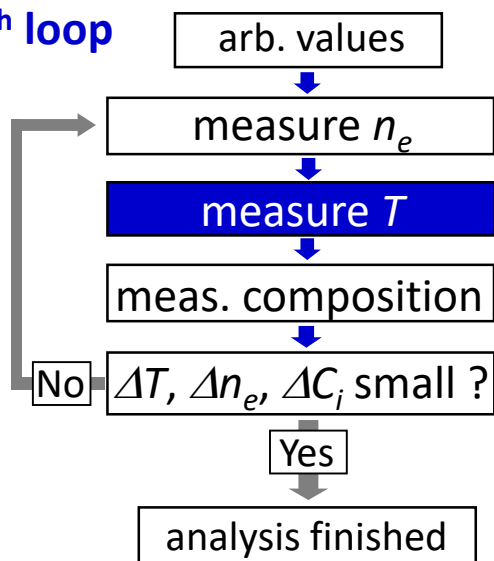
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



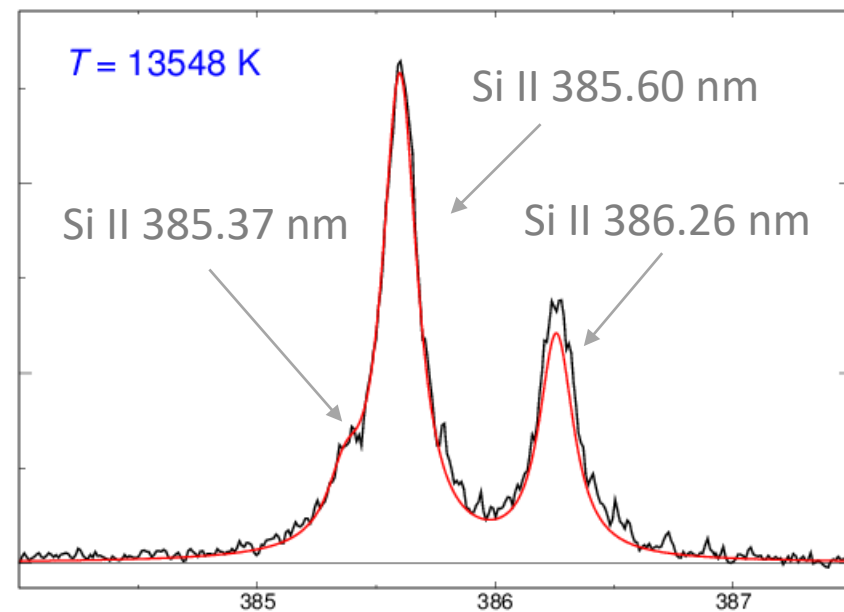
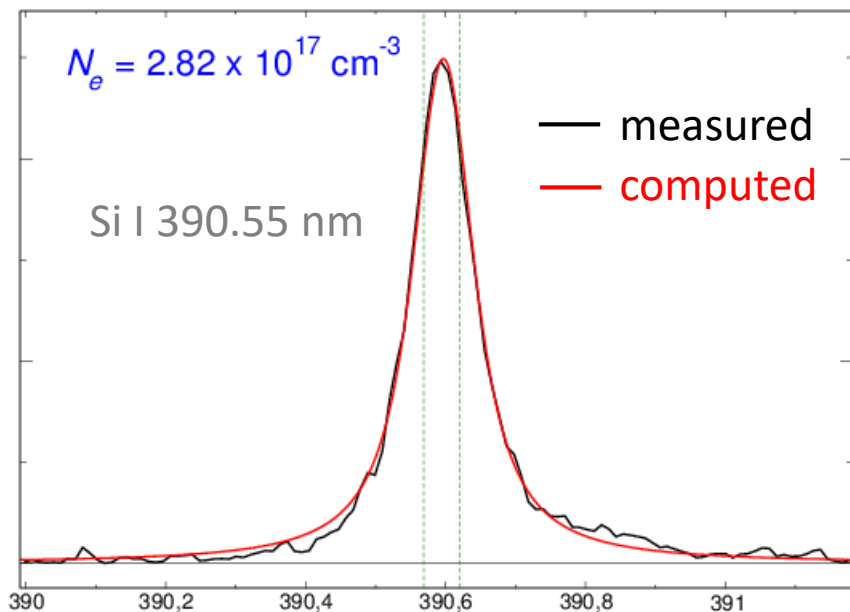
4th loop



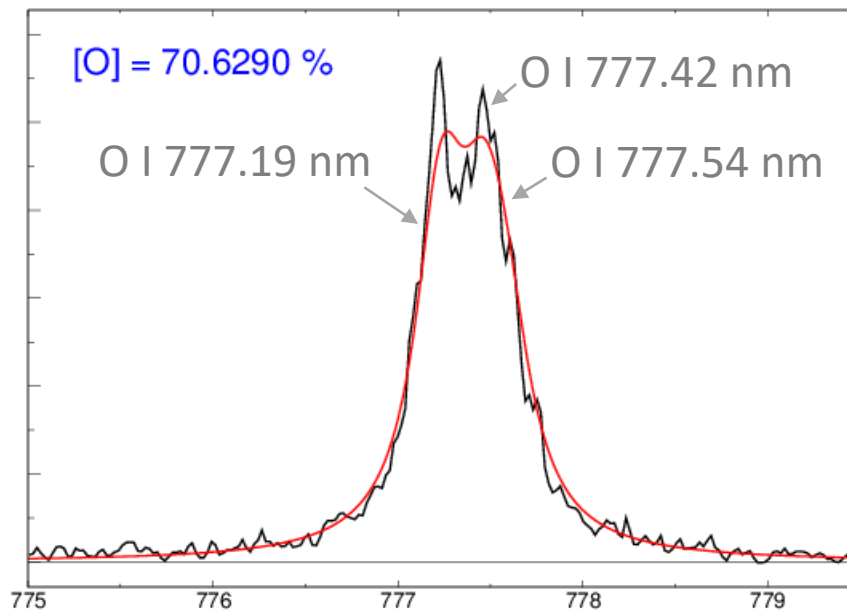
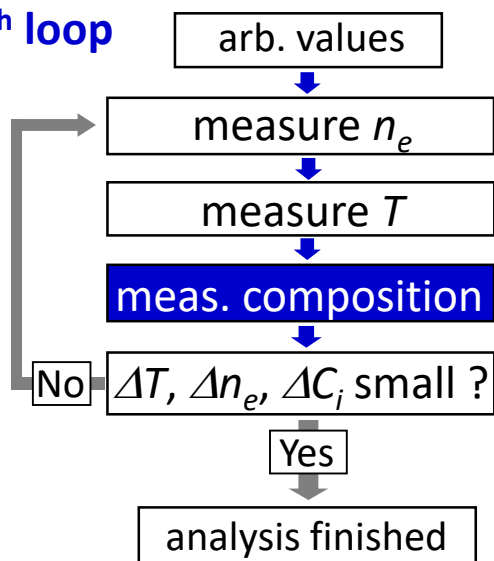
laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

analysis of fused silica



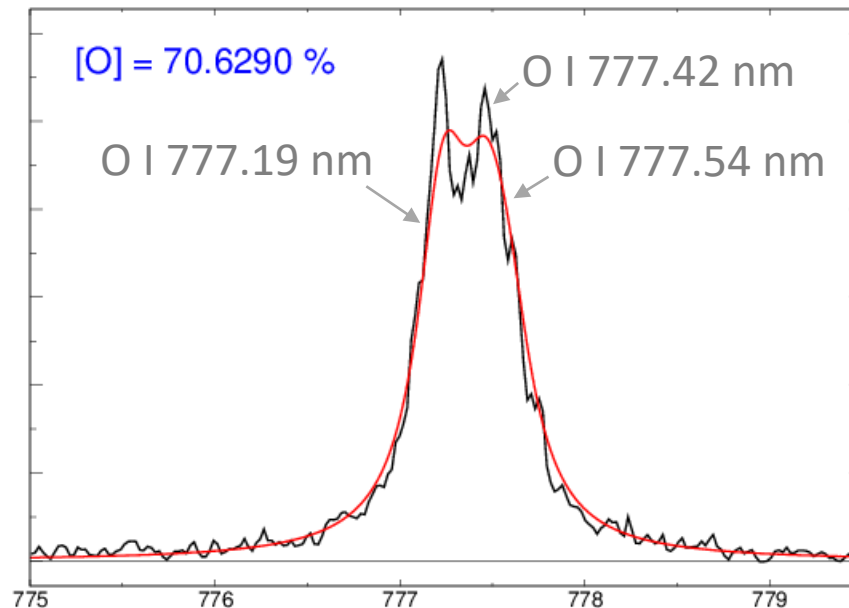
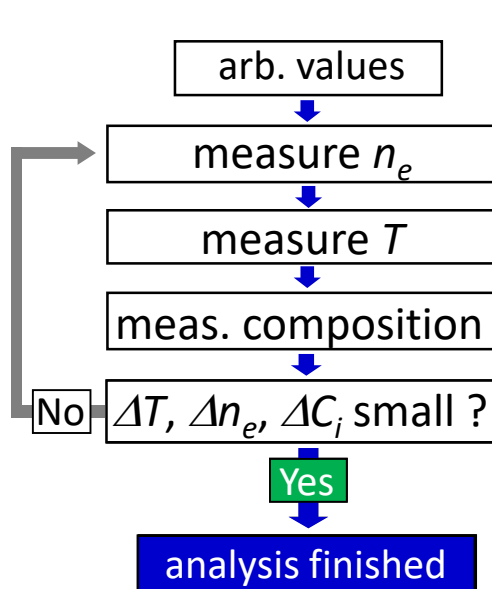
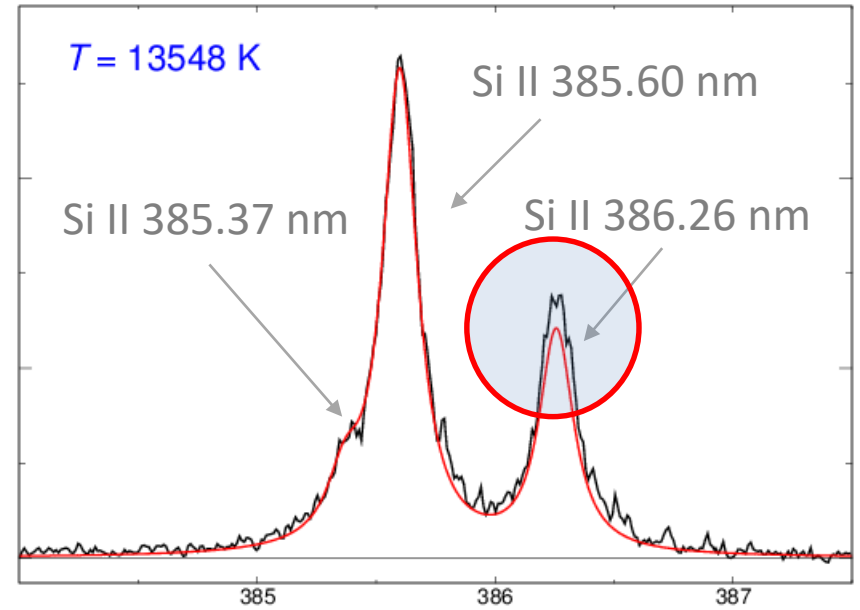
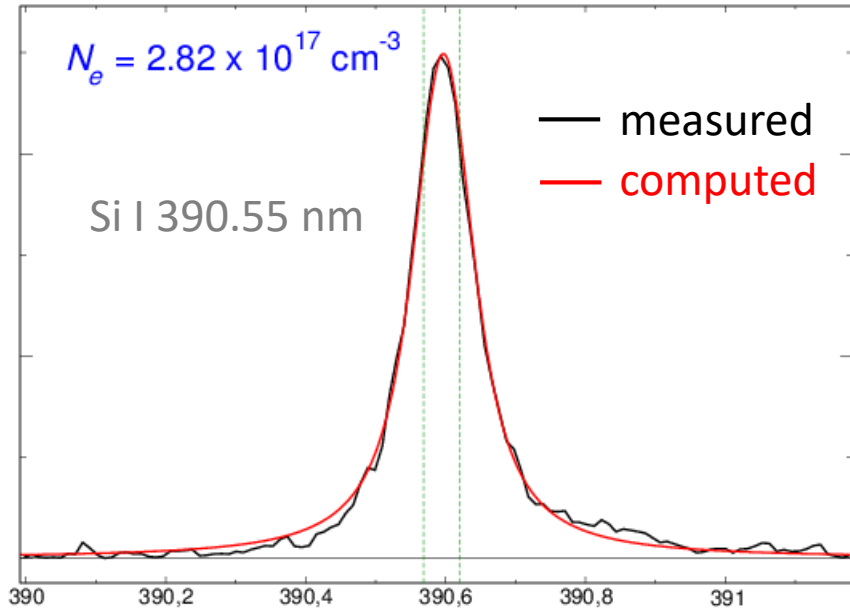
4th loop



laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

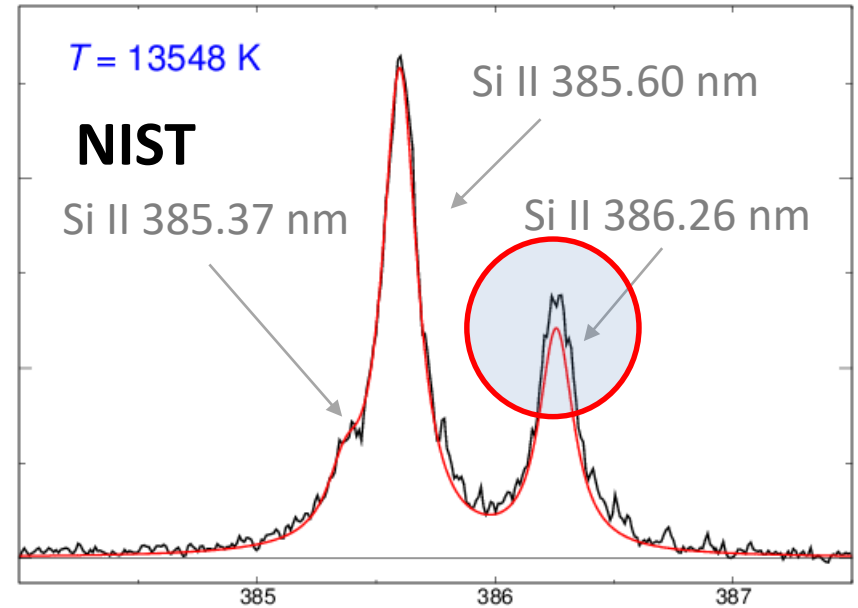
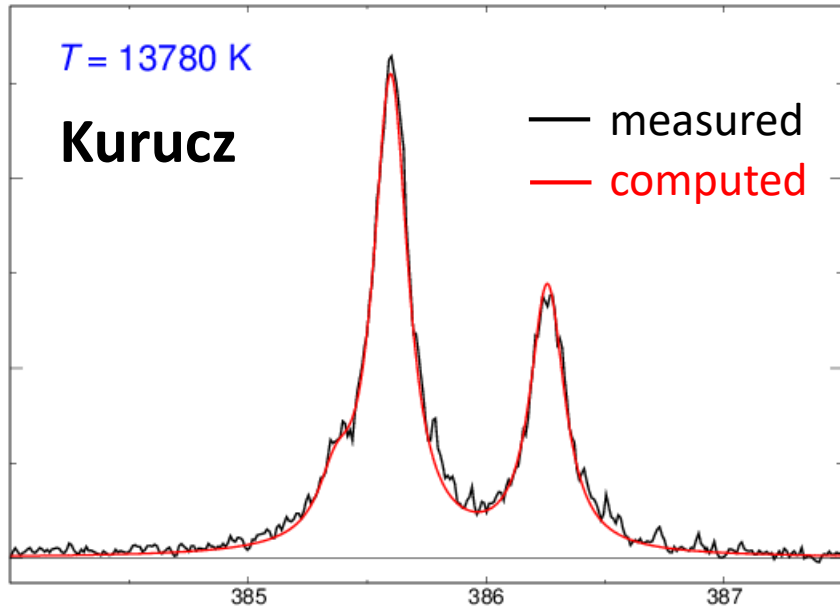
analysis of fused silica



laser: 266 nm, 8 mJ
100 Jcm⁻²
gas: argon, 5×10⁴ Pa
gate: (500 ± 100) ns

NIST data

NIST vs Kurucz databases



NIST

Ion	Ritz Wavelength Air (nm)	Rel. Int. (?)	A_{ki} (s^{-1})	Acc.	E_i (cm^{-1})	E_k (cm^{-1})	Lower Level Conf., Term, J	Upper Level Conf., Term, J	
Si II	385.3665	100w	5.11e+06	C					
Si II	385.6018	500w	4.40e+07	C+					
Si II	386.2595	200w	3.91e+07	C+					
Si I	390.5523	300	1.33e+07	B					
							Kurucz	NIST	rel. error
n_e (cm^{-3})							2.8×10^{17}	2.8×10^{17}	25%
T (K)							13,800	13,500	5%
Si (%)							34.7	29.4	14%
O (%)							65.2	70.6	6%

Kurucz

Wl / nm A-Value Element E_

vac<200nm<air / 1/s (Name)

385.3665	3.412e+06	Si II	55309.350	1.5	s3p2	2D	81251.320	1.5	4p	2P
385.6018	3.108e+07	Si II	55325.180	2.5	s3p2	2D	81251.320	1.5	4p	2P
386.2595	3.405e+07	Si II	55309.350	1.5	s3p2	2D	81191.340	0.5	4p	2P
390.5523	1.184e+07	Si I	15394.370	0.0	3p2	1S	40991.884	1.0	p4s	1P



Introduction

- Principle and historical background

Validity conditions of physical model

Methods of calibration-free measurements

Critical review of analytical performance

Recommendations

Practical advice

Critical review of analytical performance

many CF-LIBS studies \Rightarrow low accuracy for minor and trace elements

What is the origin of large measurements errors ?

\Rightarrow often attributed closure condition $(\sum_A C_A = 1)$ *Gornushkin et al., SAB 2018*

Small errors of major elements induce large errors on trace minor elements ?

mass fraction of element A : $C_A = \frac{n_A m_A}{\rho_{tot}}$ $\rho_{tot} = \sum_A n_A m_A$

fraction measurement error: $\frac{\Delta C_A}{C_A} = \sqrt{(1 - C_A)^2 \left(\frac{\Delta n_A}{n_A}\right)^2 + \sum_{j \neq A}^N C_j^2 \left(\frac{\Delta n_j}{n_j}\right)^2}$

largest contribution of minor element errors

\Rightarrow does not originate from uncertainties of major elements

Critical review of analytical performance

many CF-LIBS studies → low accuracy for minor and trace elements

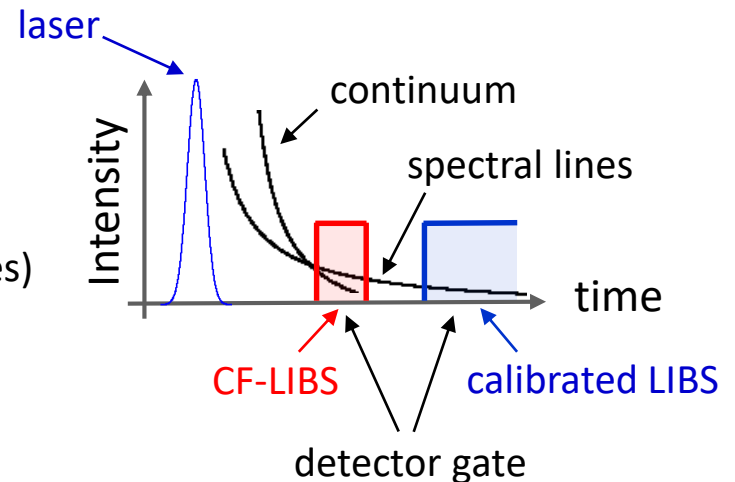
What is the origin of large measurements errors ?

→ low signal-to-noise ratio

- CF-LIBS needs LTE validity
- ⇒ large electron density required
- ⇒ intense continuum (collisions between charged particles)

situation worse with organic materials

- C, H, N, O have large energy gaps
- ⇒ LTE establishment more difficult
- ⇒ higher N_e required
- ⇒ continuum more intense



Critical review of analytical performance

many CF-LIBS studies → low accuracy for minor and trace elements

What is the origin of large measurements errors ?

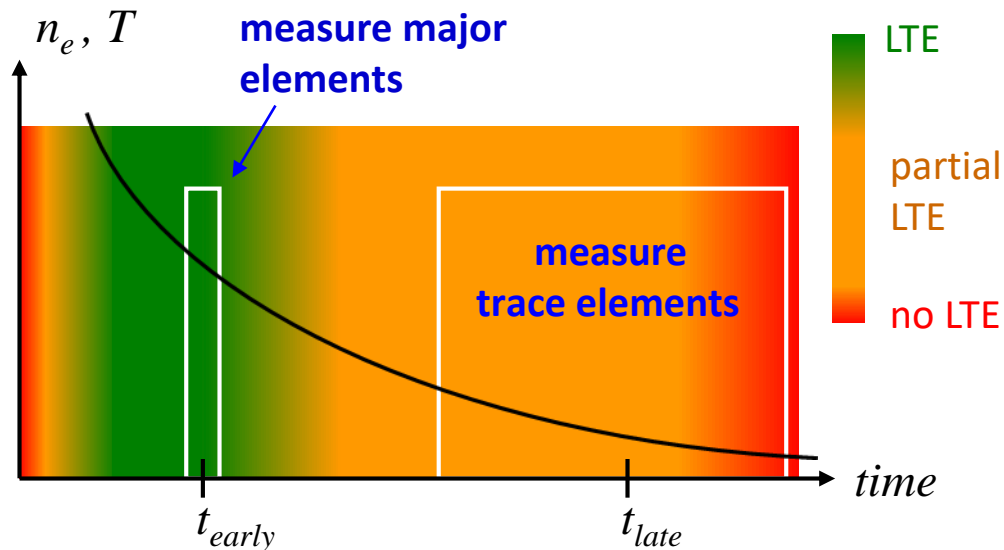
Chen et al., SAB 2018

→ low signal-to-noise ratio

solution = two-step procedure

1. early measurement

- large N_e
- ⇒ full LTE
- ⇒ low signal-to-noise
- measure major elements



2. late measurement

- reduced N_e
- ⇒ partial LTE
- ⇒ high signal-to-noise
- measure minor and trace elements

C, H, N and O out of equilibrium

→ enhanced CF-LIBS sensitivity

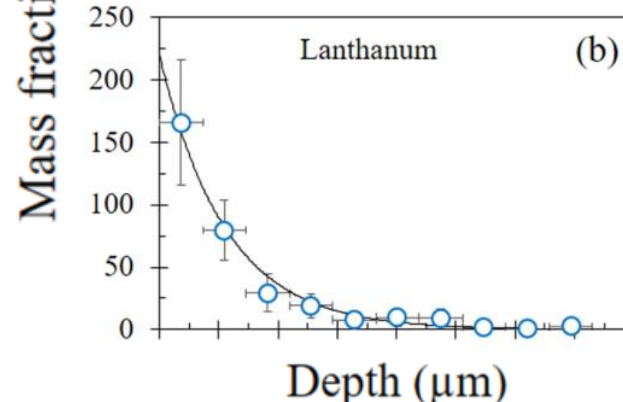
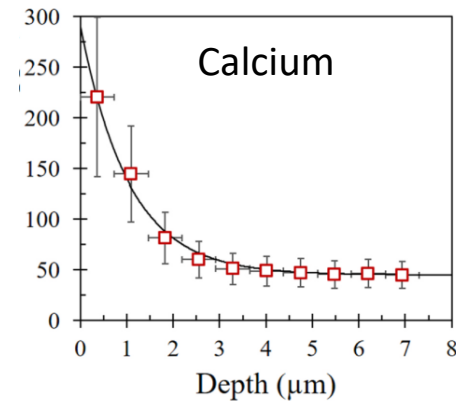
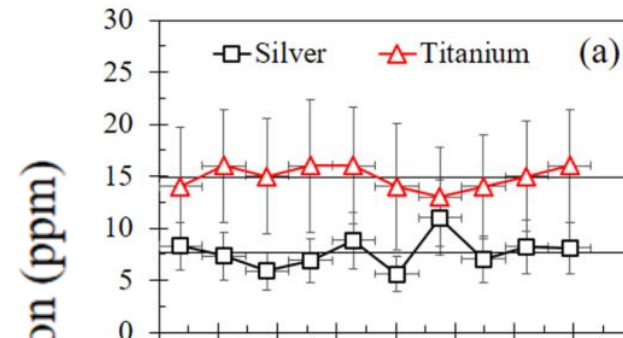
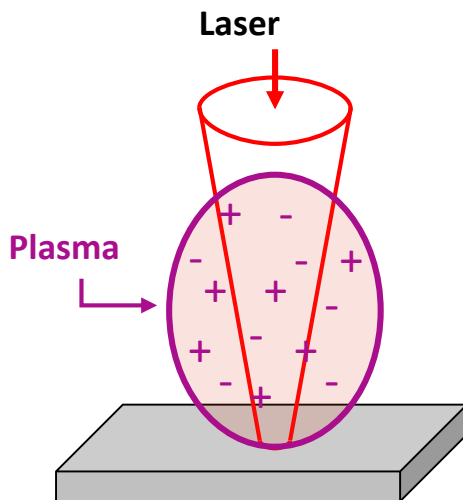
Critical review of analytical performance

many CF-LIBS studies → low accuracy for minor and trace elements

What is the origin of large measurements errors ?

→ trace element fractions on surface differ from those of bulk

SF5 heavy flint glass



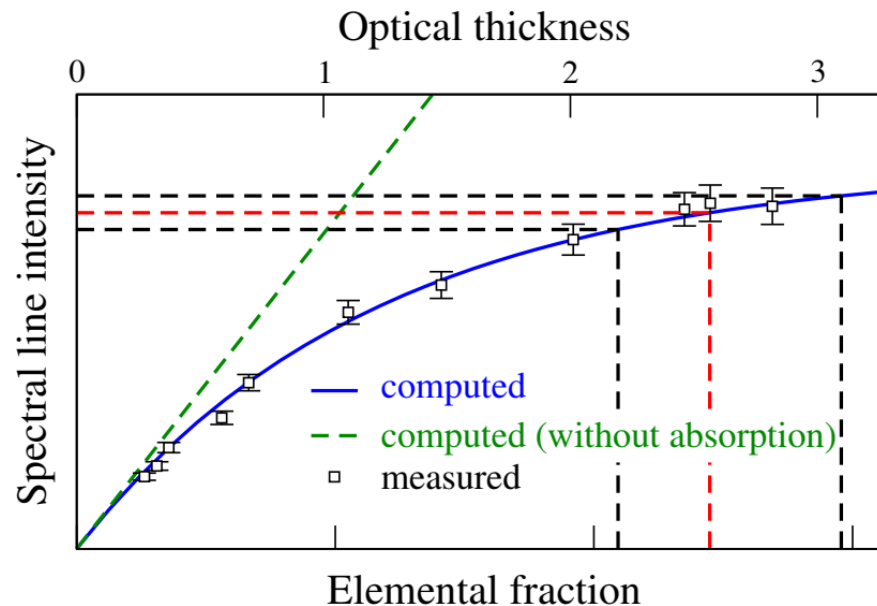
→ La in surface polishing agent

→ Ca in water of polishing solution

Critical review of analytical performance

What is the error due to self-absorption ?

⇒ Spectral radiance $B_\lambda = U_\lambda(1 - e^{-\tau})$

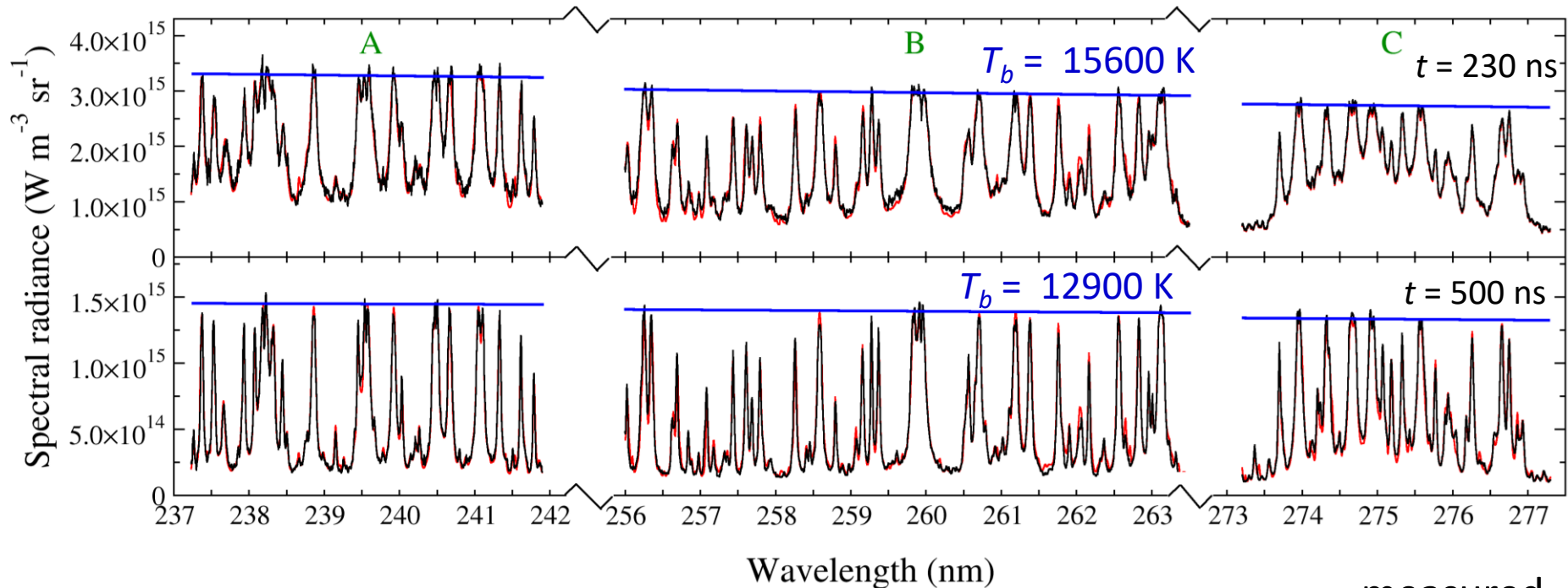


☞ strong self-absorption ($\tau \gg 1$) ⇒ $B_\lambda = U_\lambda$

⇒ strong lines saturate at blackbody radiance

Critical review of analytical performance

What is the error due to self-absorption ?



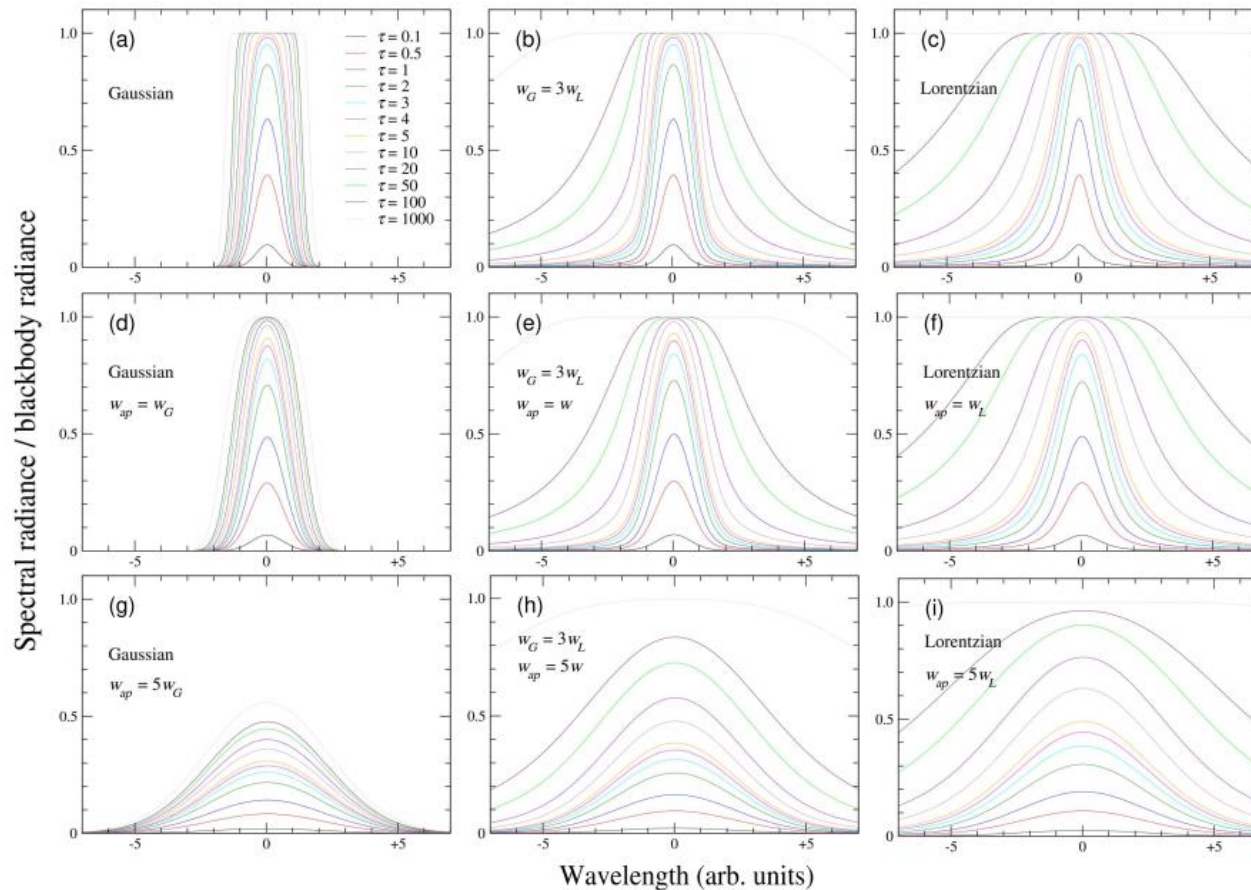
☞ strong self-absorption ($\tau \gg 1$) $\Rightarrow B_\lambda = U_\lambda$

⇒ strong lines saturate at blackbody radiance

— measured
— computed
— blackbody

Critical review of analytical performance

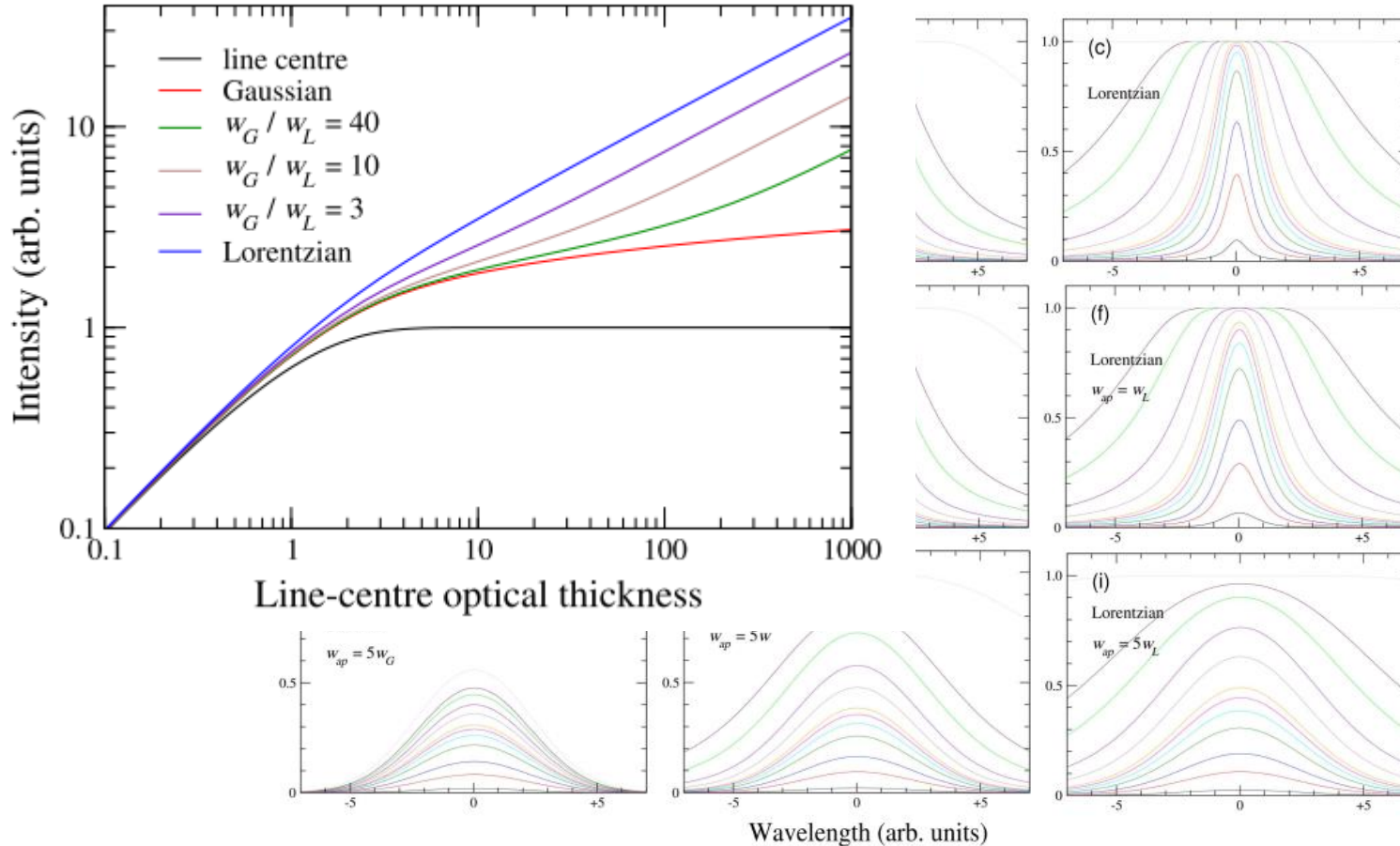
What is the error due to self-absorption ?



Intensity lowering due self-absorption to depends on line shape

Critical review of analytical performance

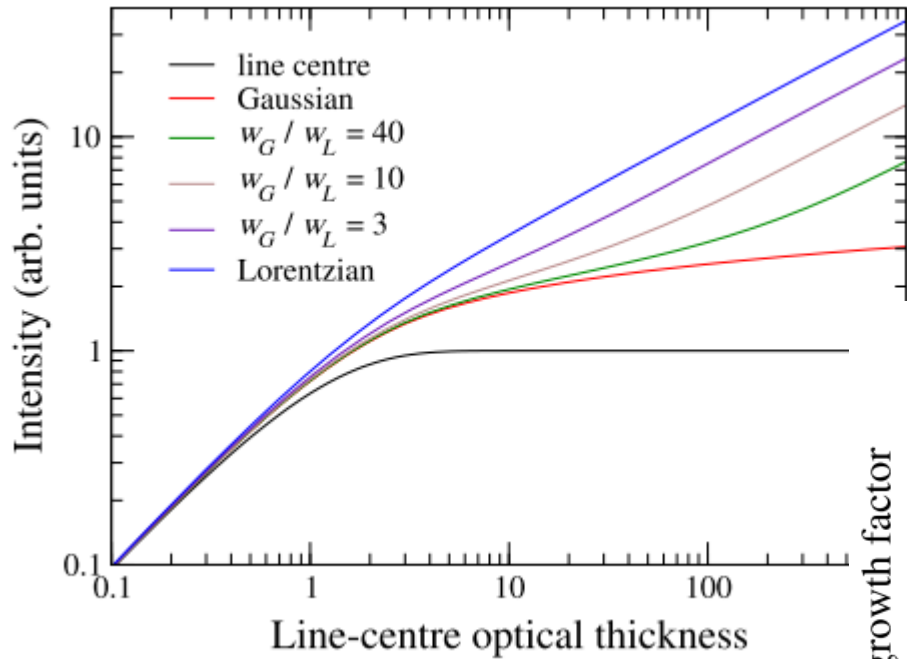
What is the error due to self-absorption ?



Intensity lowering due self-absorption to depends on line shape

Critical review of analytical performance

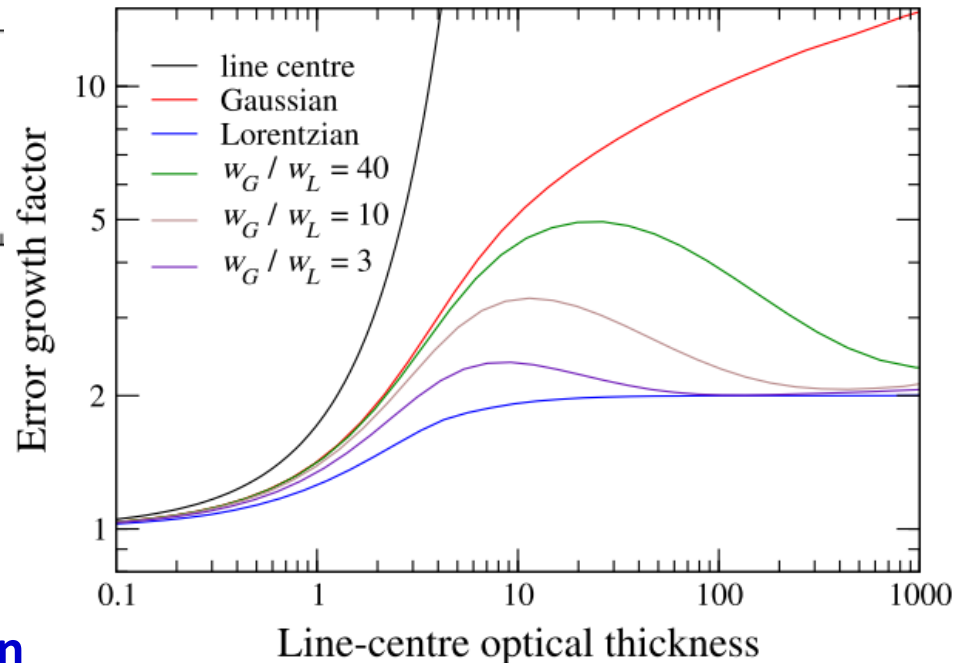
What is the error due to self-absorption ?



$$I = f(\tau_0)$$

derivative of inverse function

$$\frac{\Delta\tau_0}{\tau_0} = \frac{1}{\tau_0} \frac{f(\tau_0)}{f'(\tau_0)} \frac{\Delta I}{I} \equiv g(\tau_0) \frac{\Delta I}{I}$$



👉 error growth due to self-absorption

Critical review of analytical performance

What are the principal error sources ?

using rigorous error calculations we obtain

Taleb et al., SAB 2021

optically thin case ($\tau \ll 1$) :

$$\frac{\Delta n_A}{n_A} = \sqrt{\left(\frac{\Delta I}{I}\right)^2 + \left(\frac{\Delta A_{ul}}{A_{ul}}\right)^2}$$

ΔI = intensity measurement error (signal-to-noise ratio, apparatus response, line interference, ...)

ΔA_{ul} = uncertainty of transition probability

general case :

$$\frac{\Delta n_A}{n_A} = \sqrt{\left(\frac{\Delta \tau_0}{\tau_0}\right)^2 + \left(\frac{\Delta A_{ul}}{A_{ul}}\right)^2 + (1 - e^{-\tau_0}) \left(\left(\frac{\Delta w_{sd}}{w_{sd}}\right)^2 + \left(\frac{\Delta L}{L}\right)^2 \right)}$$
$$\frac{\Delta \tau_0}{\tau_0} = \frac{1}{\tau_0} \frac{f(\tau_0)}{f'(\tau_0)} \frac{\Delta I}{I} \equiv g(\tau_0) \frac{\Delta I}{I}$$

Δw_{sd} = uncertainty of line width

ΔL = uncertainty of plasma diameter

} large errors, 10% in best case

if w_{sd} and L are precisely known

⇒ strongly self-absorbed lines can be used for CF-LIBS



Introduction

- Principle and historical background

Validity conditions of physical model

Methods of calibration-free measurements

Critical review of analytical performance

Recommendations

Practical advice

Recommendations

Apparatus requirements

spectrometer:

CF-LIBS ☞ all sample composing elements have to be measured

⇒ observation of broadband spectral range

n_e -measurement, evaluation of self-absorption ⇒ high resolving power

☞ **echelle spectrometer**

Recommendations

Apparatus requirements

spectrometer: ☞ **echelle type**

sample holder:

echelle spectrometers suffer low sensitivity

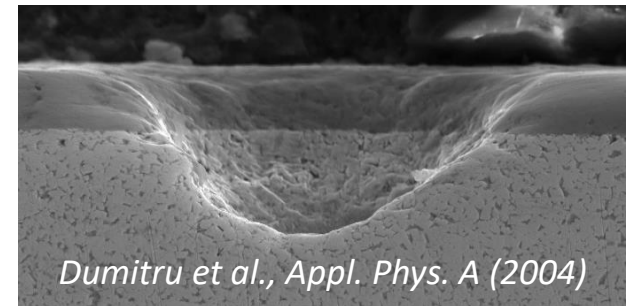
⇒ signal acquisition over large number of laser ablation events (≥ 100)

reproducible plasma generation ☞ avoid deep drilling

crater depth \ll crater diameter

⇒ apply a few laser pulses per site (5, 10, 20)

☞ **motorized sample holder**



Recommendations

Apparatus requirements

spectrometer: ☞ **echelle type**

sample holder: ☞ **motorized**

apparatus response correction:

apparatus response typically measured with radiation standards

UV range (200 – 400 nm) ☞ deuterium arc

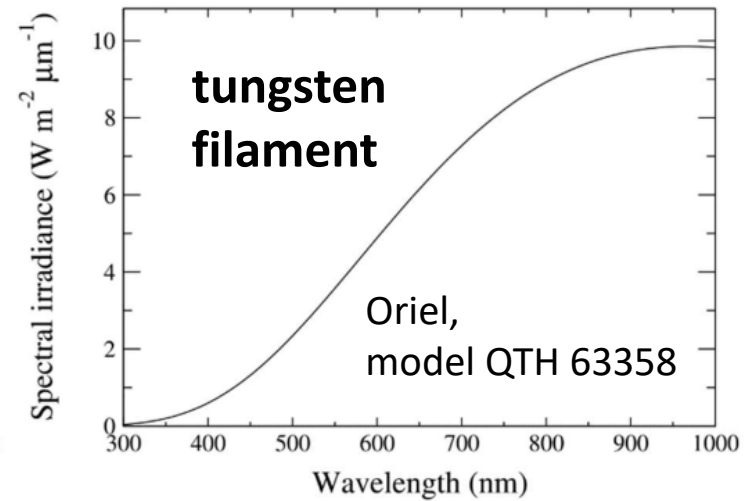
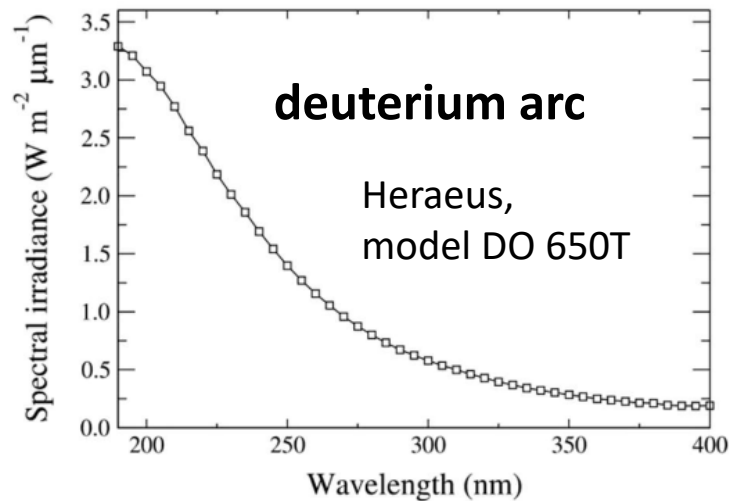
VIS/NIR range (≥ 400 nm) ☞ tungsten filament

☞ **calibration of echelle spectrometers challenging**

due to significant intensity variation on broad spectral range

Recommendations

Apparatus requirements



- ☞ **calibration of echelle spectrometers challenging**
due to significant intensity variation on broad spectral range

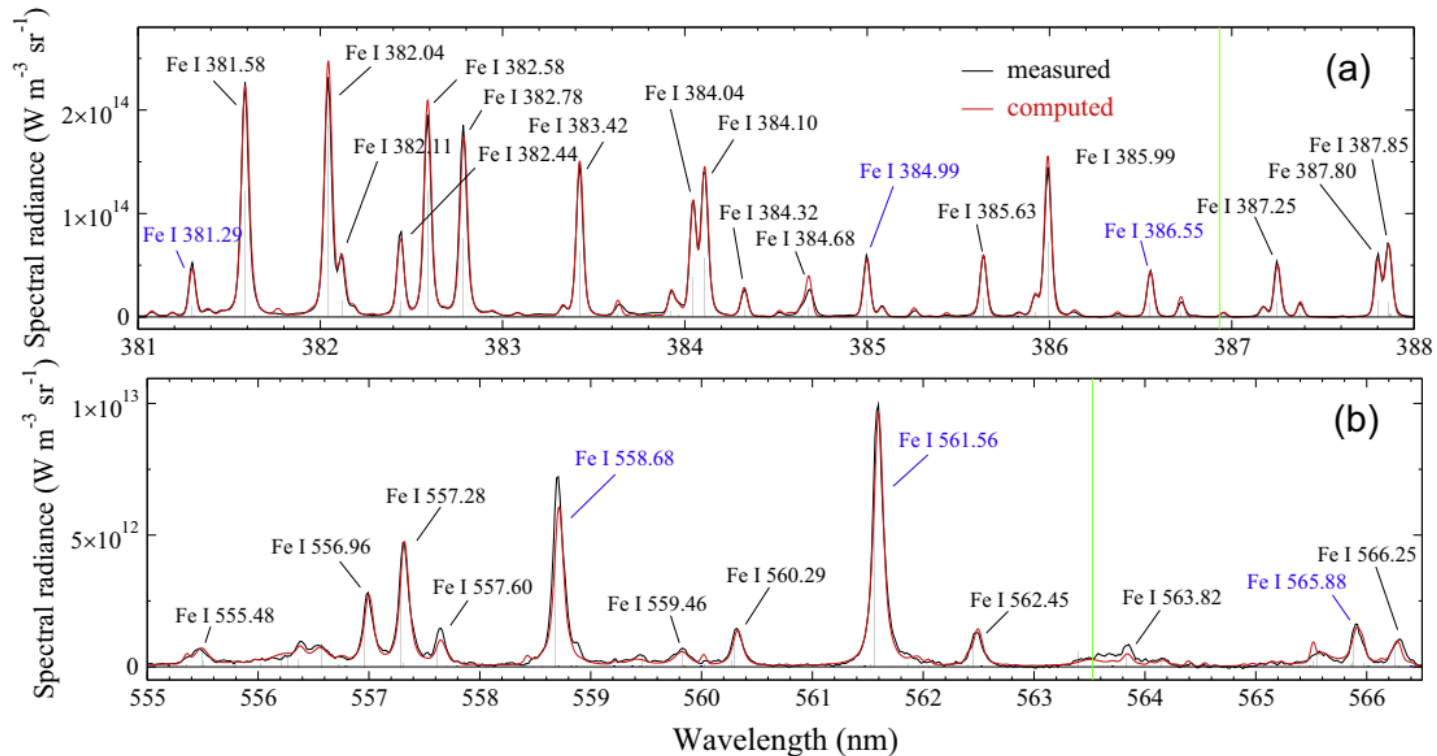
situation is worse with compact radiation standards

- ☞ **method for checking and correcting apparatus response**

Etalonnage du spectromètre par plasma laser

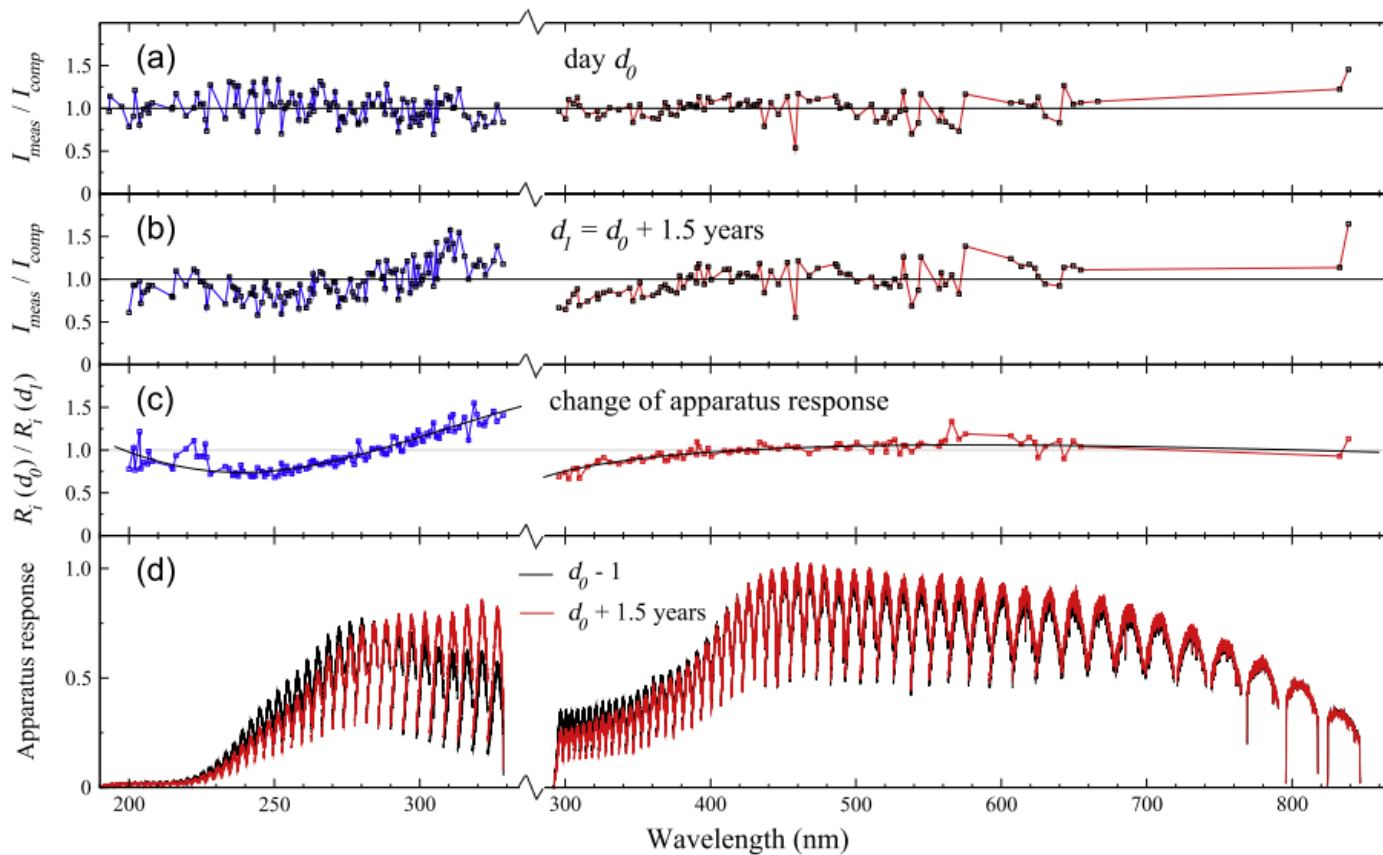
plasma uniforme en ETL \rightarrow calcul précis du spectre

ablation de l'acier \rightarrow spectre riche, valeurs A_{ul} précises sur NIST



Réponse de l'appareil déduite du rapport I_{mes} / I_{comp}

Etalonnage du spectromètre par plasma laser



écart-type des fluctuations = intervalle de confiance moyenne des $A_{ul} = 15\%$

👉 **plasma laser = moyen pour mesurer A_{ul}**

Recommendations

Apparatus requirements

spectrometer: ✎ echelle type

sample holder: ✎ motorized

apparatus response correction: ✎ radiation standards,
checking with laser plasma on steel

Experimental conditions

laser: pulse energy \Rightarrow plasma lifetime $\Rightarrow E_{min}$ required for LTE
 \Rightarrow ablated mass \Rightarrow self-absorption } a few mJ
for UV laser

Recommendations

Apparatus requirements

spectrometer: ☞ **echelle type**

sample holder: ☞ **motorized**

apparatus response correction: ☞ **radiation standards,
checking with laser plasma on steel**

Experimental conditions

laser: pulse energy ☞ **a few mJ** (UV laser)

beam focusing ⇒ to spot of 100 μm ⇒ $F_{las} \approx 100 \text{ Jcm}^{-2}$

⇒ stoichiometric ablation

Recommendations

Apparatus requirements

spectrometer: ☞ **echelle type**

sample holder: ☞ **motorized**

apparatus response correction: ☞ **radiation standards,
checking with laser plasma on steel**

Experimental conditions

laser: pulse energy ☞ **a few mJ** (UV laser)

beam focusing ☞ **to spot of 100 μm**

pulse duration $\Rightarrow \tau_{las} > \tau_{e-i} \Rightarrow$ laser heating of expanding vapor
 \Rightarrow nanosecond laser

Recommendations

Apparatus requirements

spectrometer: ☞ **echelle type**

sample holder: ☞ **motorized**

apparatus response correction: ☞ **radiation standards,
checking with laser plasma on steel**

Experimental conditions

laser: pulse energy ☞ **a few mJ** (UV laser)

beam focusing ☞ **to spot of 100 μm**

pulse duration ☞ **nanosecond**

wavelength \Rightarrow UV radiation \Rightarrow energy deposition on sample surface
 \Rightarrow spatially uniform plasma

Recommendations

Apparatus requirements

spectrometer: ☞ **echelle type**

sample holder: ☞ **motorized**

apparatus response correction: ☞ **radiation standards,
checking with laser plasma on steel**

Experimental conditions

laser: pulse energy ☞ **a few mJ** (UV laser)

beam focusing ☞ **to spot of 100 μm**

pulse duration ☞ **nanosecond**

wavelength ☞ **UV radiation**

spectra recording: gate delay $\Rightarrow n_e$ large enough to ensure LTE

gate width $\Rightarrow \Delta T/T, \Delta n_e/n_e \ll 1 \Rightarrow \Delta t_{gate}$ small
 \Rightarrow S/N ratio $\Rightarrow \Delta t_{gate}$ large

} $\Delta t_{gate} = t_{delay} / 2$

Recommendations

Apparatus requirements

spectrometer: ☞ **echelle type**

sample holder: ☞ **motorized**

apparatus response correction: ☞ **radiation standards,
checking with laser plasma on steel**

Experimental conditions

laser: pulse energy ☞ **a few mJ** (UV laser)

beam focusing ☞ **to spot of 100 μm**

pulse duration ☞ **nanosecond**

wavelength ☞ **UV radiation**

spectra recording: gate delay $\Rightarrow n_e$ large enough to ensure LTE

gate width $\Rightarrow \Delta t_{gate} = t_{delay} / 2$

signal treatment \Rightarrow noise subtraction before response correction

Recommendations

Experimental conditions

laser: pulse energy	☞ a few mJ (UV laser)
beam focusing	☞ to spot of 100 μm
pulse duration	☞ nanosecond
wavelength	☞ UV radiation

spectra recording: gate delay $\Rightarrow n_e$ large enough to ensure LTE

gate width $\Rightarrow \Delta t_{gate} = t_{delay} / 2$

signal treatment \Rightarrow noise subtraction before response correction

atmospheric conditions: pressure \Rightarrow large enough to ensure LTE
 \Rightarrow low enough to minimize coll. quenching
 \Rightarrow atmospheric pressure

Recommendations

Experimental conditions

laser: pulse energy ☞ **a few mJ** (UV laser)
beam focusing ☞ **to spot of 100 μm**
pulse duration ☞ **nanosecond**
wavelength ☞ **UV radiation**

spectra recording: gate delay $\Rightarrow n_e$ large enough to ensure LTE

gate width $\Rightarrow \Delta t_{gate} = t_{delay} / 2$

signal treatment \Rightarrow noise subtraction before response correction

atmospheric conditions: pressure ☞ **atmospheric**

gas nature \Rightarrow argon \Rightarrow higher brilliance

\Rightarrow longer plasma lifetime

\Rightarrow plasma spatially uniform

Recommendations

Experimental conditions

laser: pulse energy ☞ **a few mJ** (UV laser)

beam focusing ☞ **to spot of 100 μm**

pulse duration ☞ **nanosecond**

wavelength ☞ **UV radiation**

spectra recording: gate delay $\Rightarrow n_e$ large enough to ensure LTE

gate width $\Rightarrow \Delta t_{gate} = t_{delay} / 2$

signal treatment \Rightarrow noise subtraction before response correction

atmospheric conditions: pressure ☞ **atmospheric**


gas nature ☞ **argon for improved accuracy**


laboratory environment: ☞ **T-stabilized**


Recommendations

Selection of spectral lines

transition probability A_{ul}  **highest accuracy**

upper level energy E_u  **close values of analytical lines**
 \Rightarrow reduce impact of T -measurement uncertainty

wavelength λ  **close values of analytical lines**
 \Rightarrow reduce impact of apparatus response error

optical thickness τ  **lowest**

signal-to-noise ratio  **highest**

automated choice  **minimize analytical error**

$$\frac{\Delta n_A}{n_A} = \sqrt{\left(\frac{\Delta \tau_0}{\tau_0}\right)^2 + \left(\frac{\Delta A_{ul}}{A_{ul}}\right)^2 + (1 - e^{-\tau_0}) \left(\left(\frac{\Delta w_{sd}}{w_{sd}}\right)^2 + \left(\frac{\Delta L}{L}\right)^2 \right)}$$

$$\frac{\Delta \tau_0}{\tau_0} = \frac{1}{\tau_0} \frac{f(\tau_0)}{f'(\tau_0)} \frac{\Delta I}{I} \equiv g(\tau_0) \frac{\Delta I}{I}$$



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Practical advice

How to perform CF-LIBS analysis ?

- 👉 record valid spectrum
- 👉 measure apparatus response function
- 👉 measure apparatus width as function of wavelength
- 👉 get user account on LP3 server
- 👉 deposit corrected spectrum on server
- 👉 proceed spectrum with semi-automated CF-LIBS software

In the future

- 👉 portable software will be available

Practical advice



book chapter

“Calibration-free laser-induced breakdown spectroscopy”

in

**“Laser-Induced Breakdown Spectroscopy (LIBS):
Concepts, Instrumentation, Data Analysis and Applications”**

to be published by **John Wiley & Sons Ltd**

editors **Vivek K. Singh, Y. Deguchi, Zhenzhen Wang, Durgesh K. Tripathi**

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